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# Spintronic phenomena and components for memory, logic and RF applications

**Giant MagnetoResistance**

**Benefit in magnetic recording technology**

**Tunnel Magnetoresistance**

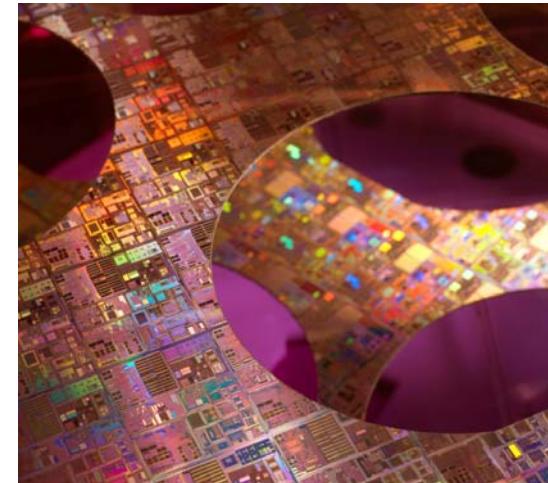
**Spin-transfer**

**Magnetic Random Access Memories (MRAM)**

**Hybrid CMOS/magnetic components for non-volatile and reprogrammable logic**

**Radio Frequency oscillators based on spin-transfer**

**Conclusion**

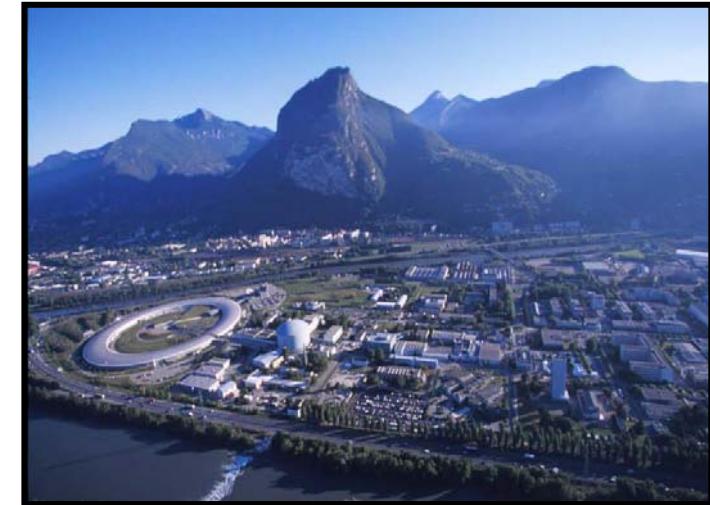


# Acknowledgements

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**HYMAGINE** (ERC2010)



# Spin electronics

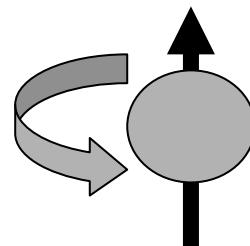
**Spin electronics or spintronics :**



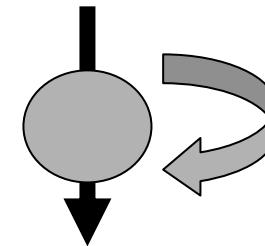
$$\text{electrons} = \text{electrical charge} + \text{spin } \uparrow \text{ or } \downarrow$$

Purpose of spin-electronics : Use spin as a new degree of freedom  
⇒ New phenomena ⇒ new components (MRAM, Logic gates, RF components)

Classical image of spin :



Spin up

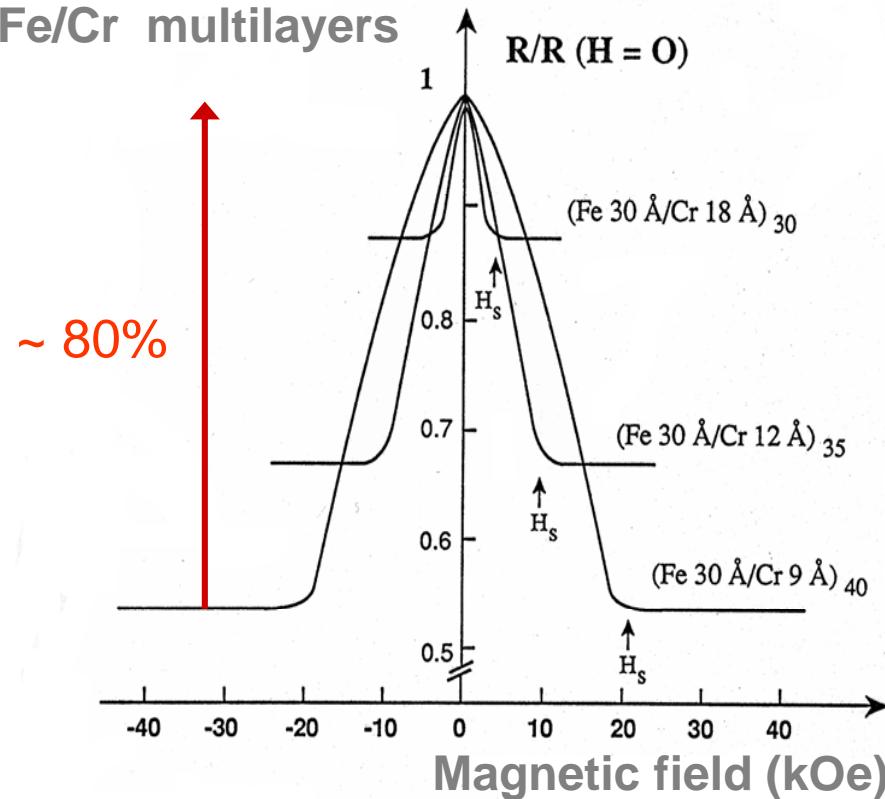


Spin down

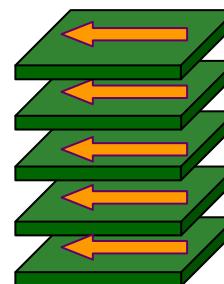
All electrons have a spin: wave function described with « up » and « down » components.  
In non-magnetic material : « up » and « down » spin populations are equal  
In magnetic material : net spin polarization parallel to magnetization (~50% in Co).

# Birth of spin electronics : Giant magnetoresistance discovery (1988)

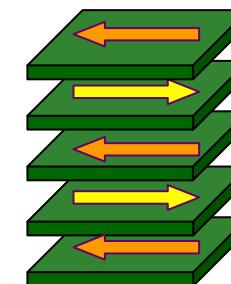
Fe/Cr multilayers



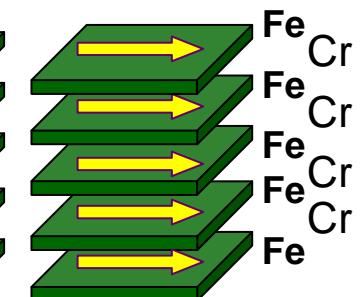
$H = -H_{sat}$



$H = 0$



$H = +H_{sat}$



Antiferromagnetically coupled multilayers

$$GMR = \frac{R_{AP} - R_p}{R_p}$$

A.Fert et al, PRL (1988);  
P.Grunberg et al, patent (1988)+PRB (1989)



Nobel Prize 2007

# Spin dependent transport in magnetic metals

Current carried in parallel by “spin up” and by “spin down” electrons

Scattering of electrons determined by DOS at  $E_F$ :

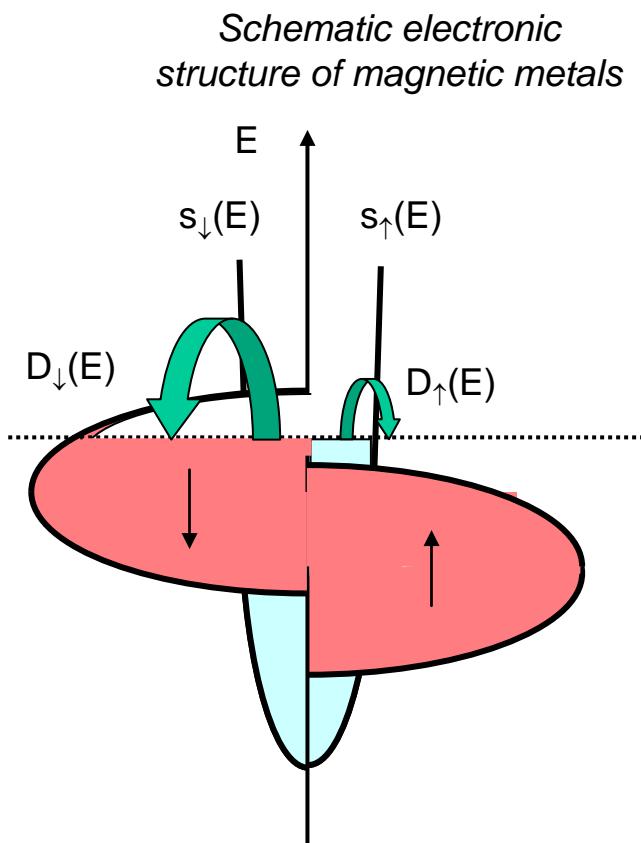
Fermi Golden rule :  $P^\sigma \propto \langle i|W|f \rangle^2 D_f(E_F)$

Different density of states at Fermi energy for spin-up and spin-down electrons

Different mean free paths and different resistivities for spin-up and spin-down electrons

Example:  $\lambda_{\uparrow Co} = 10\text{nm}$ ;  $\lambda_{\downarrow Co} = 1\text{nm}$

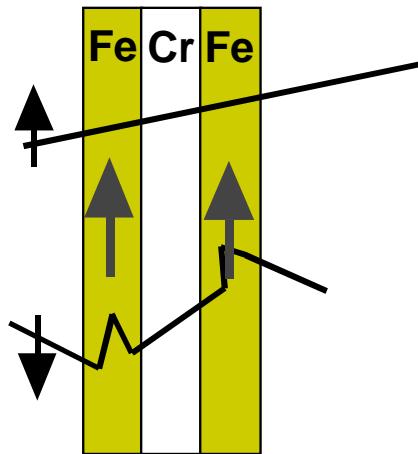
$$\rho_{\uparrow Co} = 18 \mu\Omega\cdot\text{cm} \quad \rho_{\downarrow Co} = 180 \mu\Omega\cdot\text{cm}$$



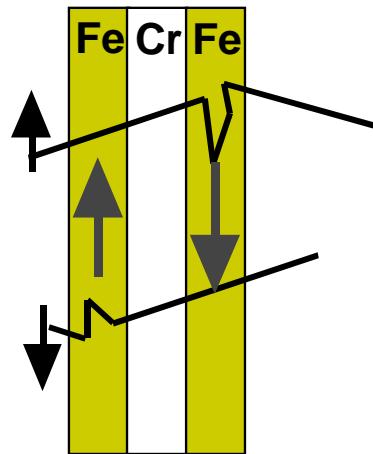
$$\rho_{Co} = \frac{\rho_{\uparrow Co} \rho_{\downarrow Co}}{\rho_{\uparrow Co} + \rho_{\downarrow Co}} = 16.4 \mu\Omega\cdot\text{cm}$$

# Simple model of Giant Magnetoresistance

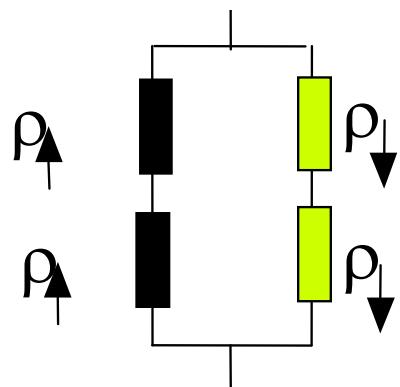
Parallel config



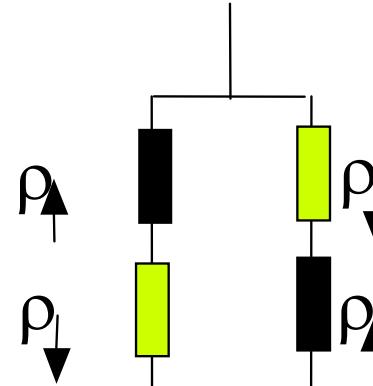
Antiparallel config



Equivalent resistances :



$$\rho_P = \frac{2\rho_{\uparrow}\rho_{\downarrow}}{(\rho_{\uparrow} + \rho_{\downarrow})}$$



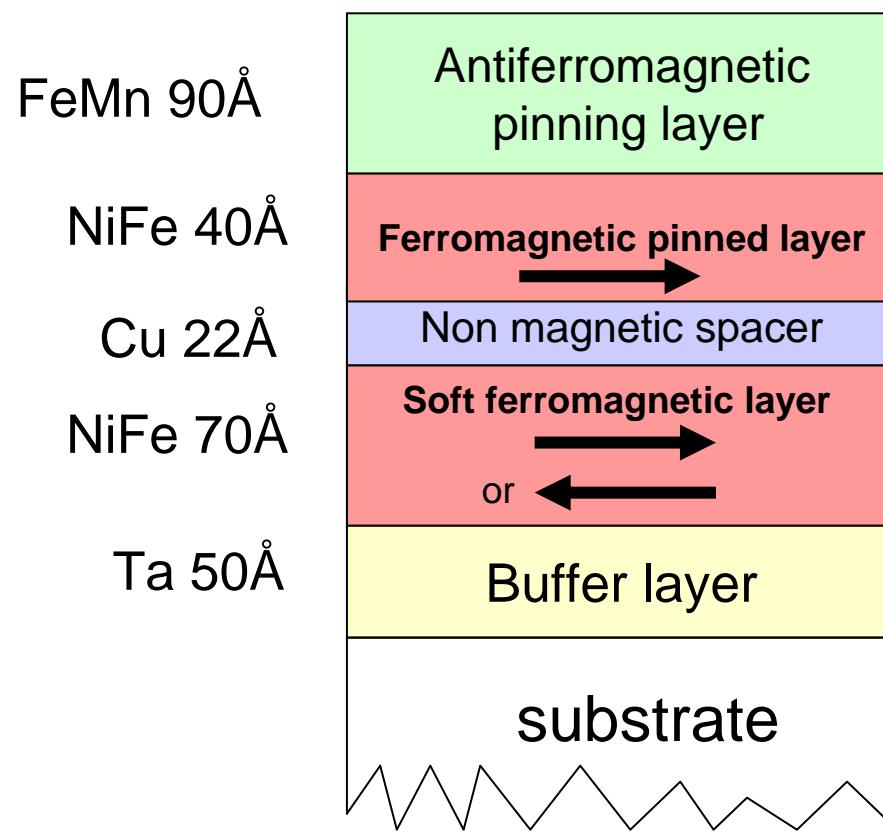
$$\rho_{AP} = \frac{(\rho_{\uparrow} + \rho_{\downarrow})}{2}$$

$$\frac{\Delta\rho}{\rho_{ap}} = \left( \frac{\rho_{\uparrow} - \rho_{\downarrow}}{\rho_{\uparrow} + \rho_{\downarrow}} \right)^2 = \left( \frac{\alpha - 1}{\alpha + 1} \right)^2$$

$$\alpha = \frac{\rho_{\uparrow}}{\rho_{\downarrow}}$$

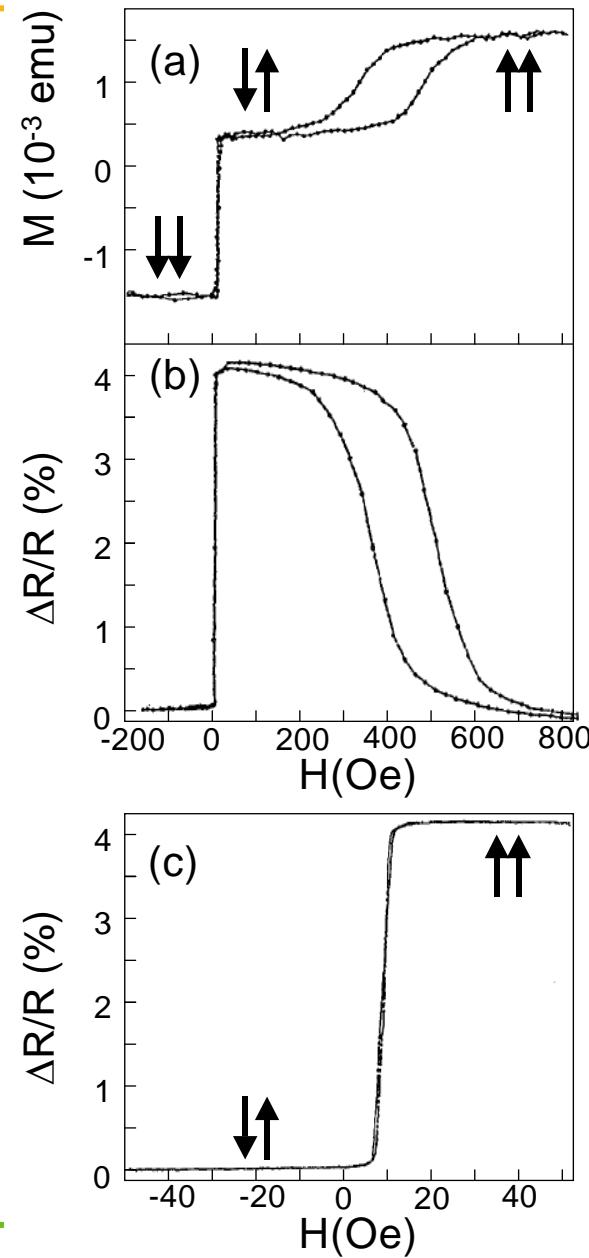
Key role of  
scattering contrast  $\alpha$

## Low field GMR: Spin-valves



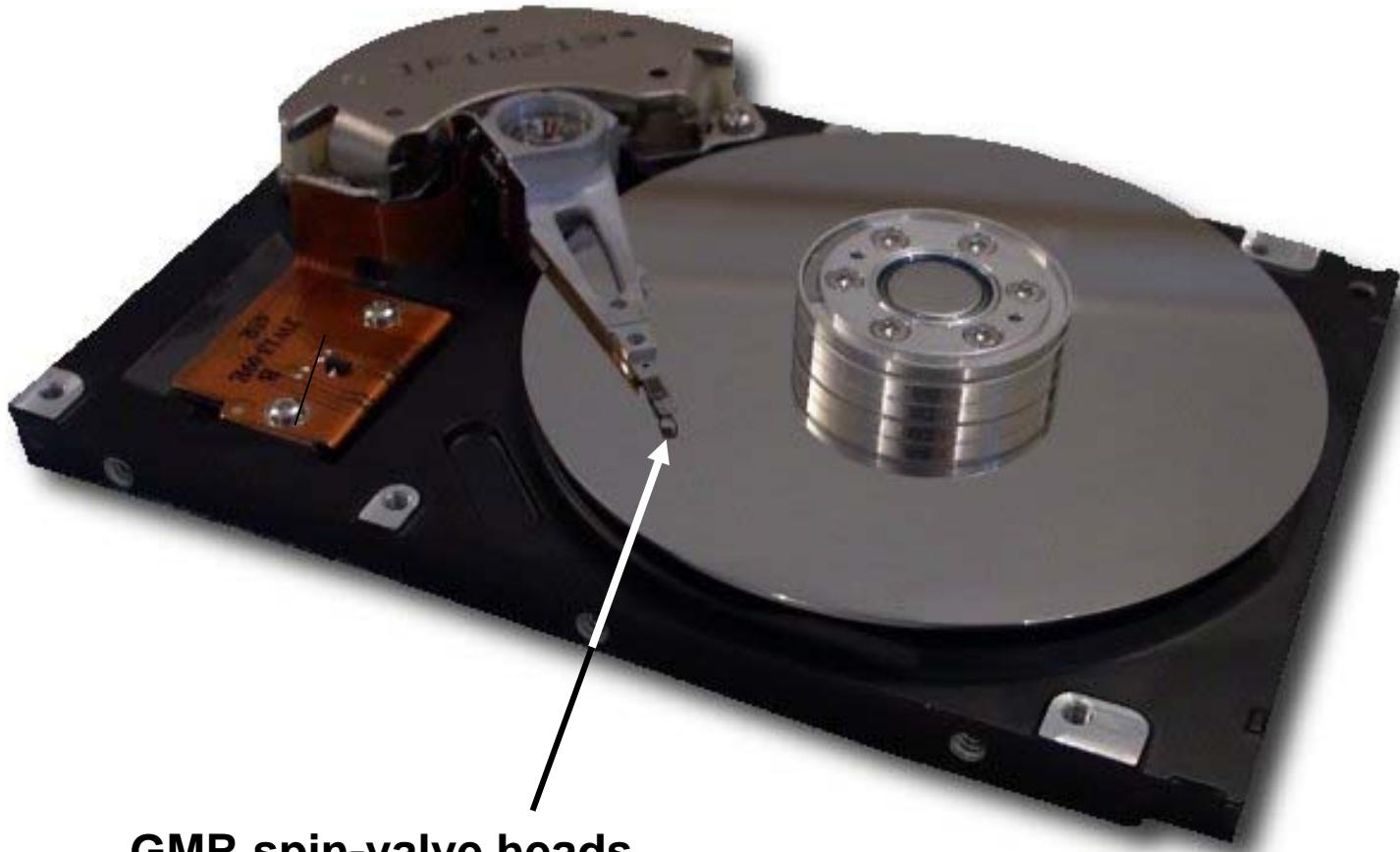
- Ultrasensitive magnetic field sensors (MR heads)
- Spin engineering of magnetic multilayers

B.Dieny et al, Phys.Rev.B.(1991)+patent US5206590 (1991).



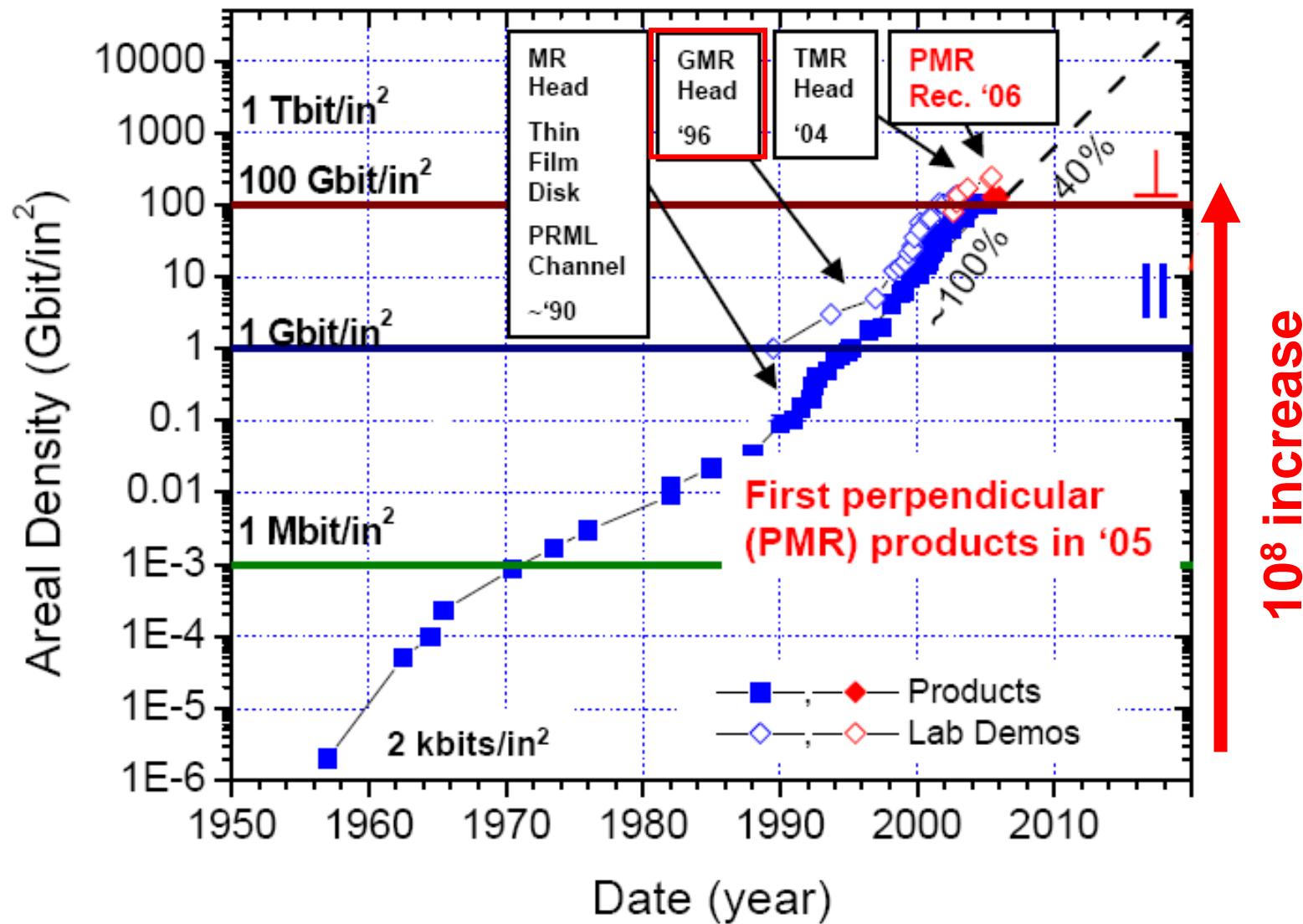
## Benefit of GMR in magnetic recording

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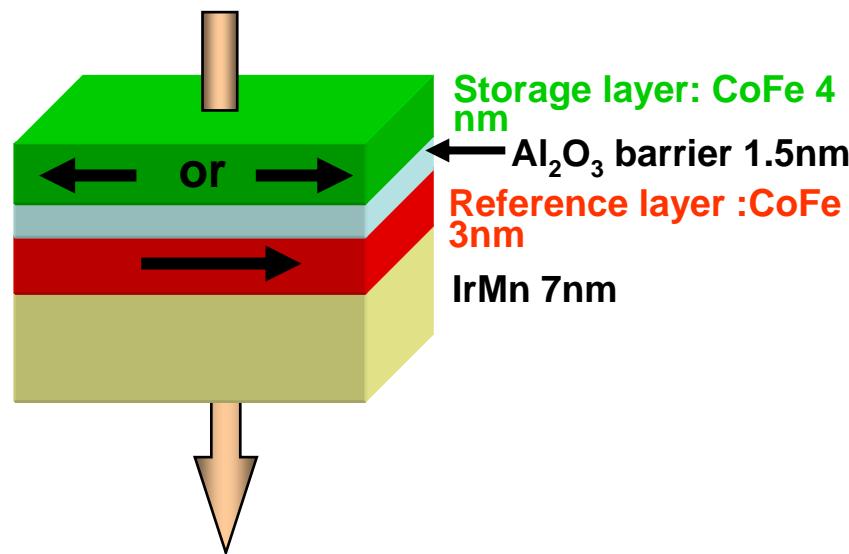
**GMR spin-valve heads  
from 1998 to 2004**

## Dramatic increase in areal storage density over the past 50 years



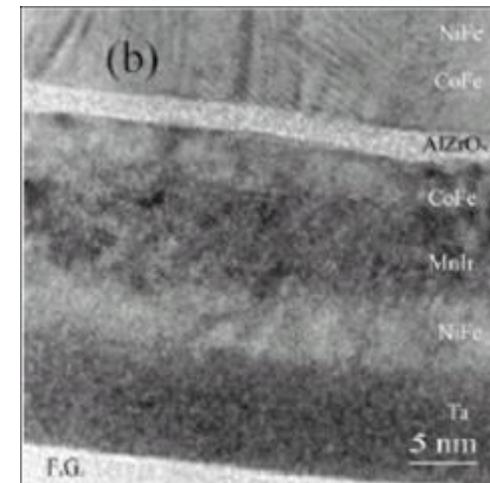
# Magnetic tunnel junctions - Tunnel magnetoresistance

Structure of a magnetic tunnel junction

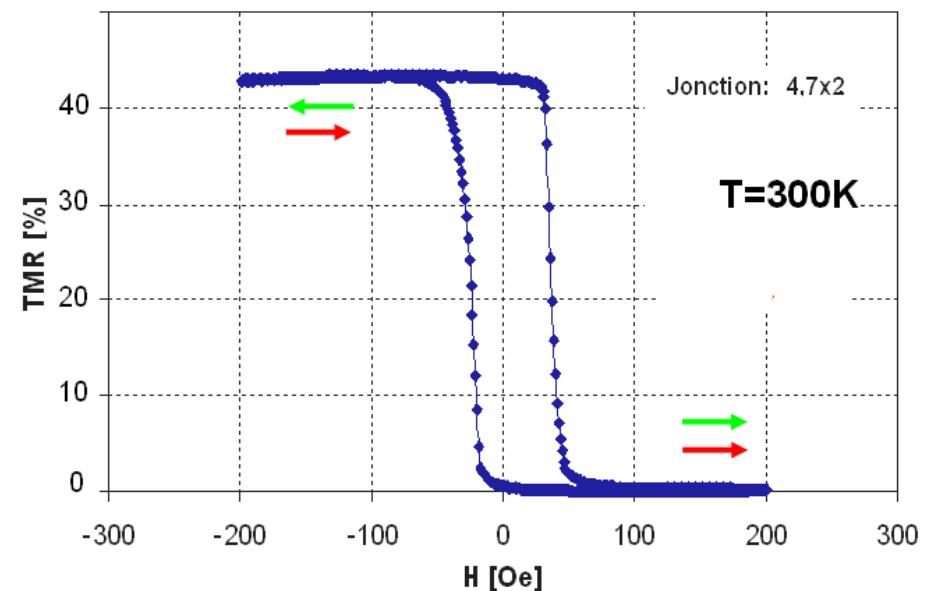


Acts as a couple polarizer/analyzer with the spin of the electrons.

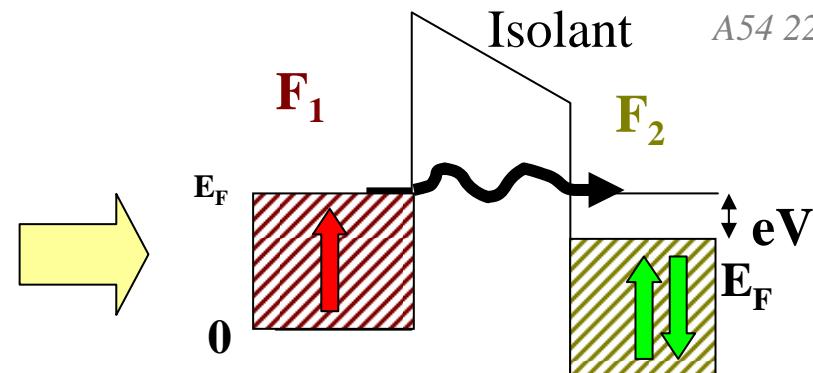
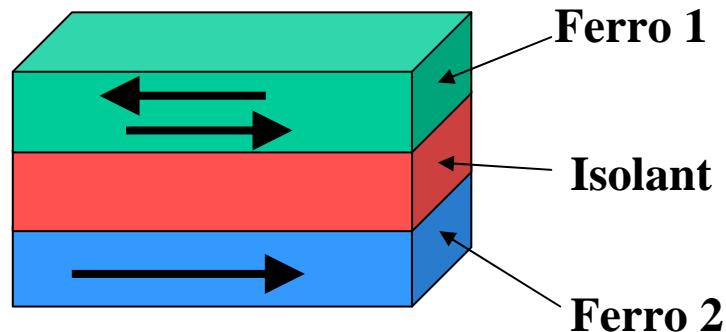
- First observation of TMR at low T in MTJ:  
Julliere (1975) (Fe/Ge/Co)
- TMR at 300K :  
Moodera *et al*, PRL (1995);  
Myazaki *et al*, JMMM(1995).  $\Delta R/R \sim 50\%$   
in AlO<sub>x</sub> based junctions



Al(Zr)O<sub>x</sub>



## Julliere model of TMR



Jullière, Phys. Lett.  
A54 225 (1975)

Fermi Golden rule: proba of tunneling

$$P^\sigma \propto \langle i | W | f \rangle^2 D_f(E_F) \\ \propto D_i(E_F)$$

Nb of electrons candidate for tunneling

$$J^\sigma \propto D_1^\sigma(E_F) \times D_2^\sigma(E_F)$$

⇒ tunneling current in each spin channel

Parallel configuration

$$J^{parallel} \propto D_1^\uparrow D_2^\uparrow + D_1^\downarrow D_2^\downarrow$$

$$P = \frac{D^\uparrow(E_F) - D^\downarrow(E_F)}{D^\uparrow(E_F) + D^\downarrow(E_F)}$$

$$TMR = \frac{\Delta R}{R_P} = \frac{2 P_1 P_2}{1 - P_1 P_2}$$

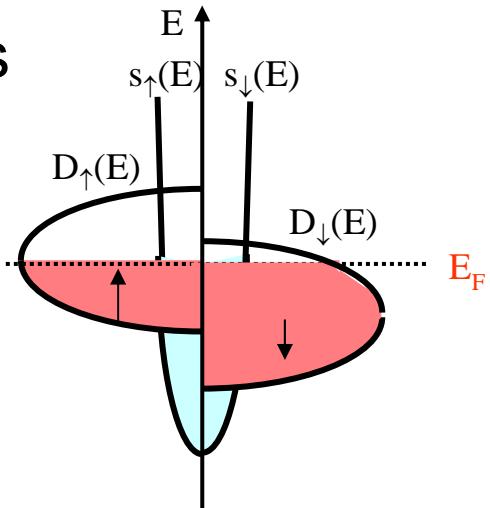
Antiparallel configuration

$$J^{antiparallel} \propto D_1^\uparrow D_2^\downarrow + D_1^\downarrow D_2^\uparrow$$

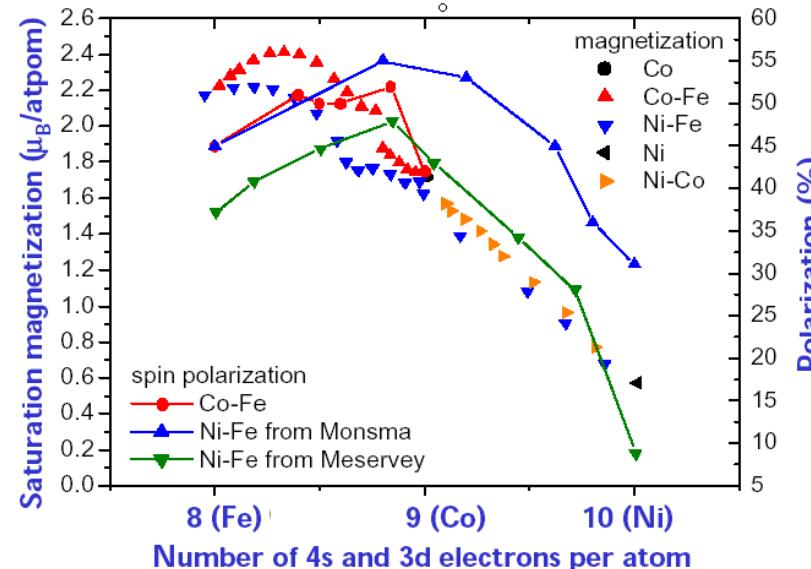
$$TMR = \frac{\Delta R}{R_{AP}} = \frac{2 P_1 P_2}{1 + P_1 P_2}$$

# Spin polarization of 3d metals

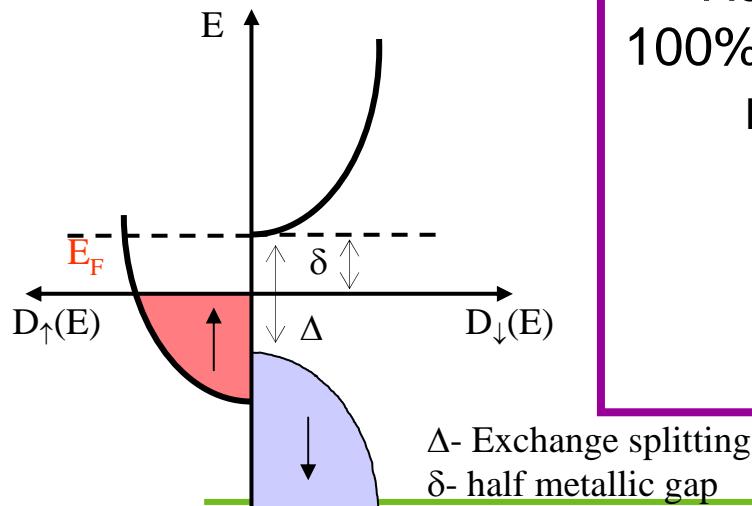
Metals



Parkin  
et al



Half metals



Half metals are  
100% spin polarized !

Heusler alloys

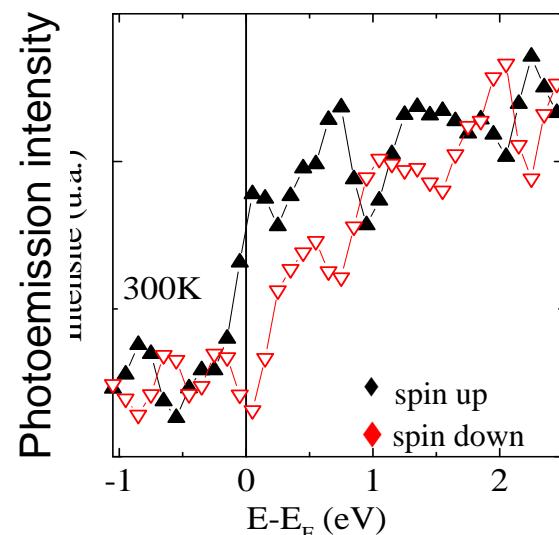
$\text{LaSrMnO}_3$

$\text{Fe}_3\text{O}_4$

$\text{CrO}_2$

...

NiMnSb (*Ristoiu et al.*)



# Giant TMR of MgO tunnel barriers

S.S.P.Parkin et al, *Nature Mat.* (2004), *nmat1256*.

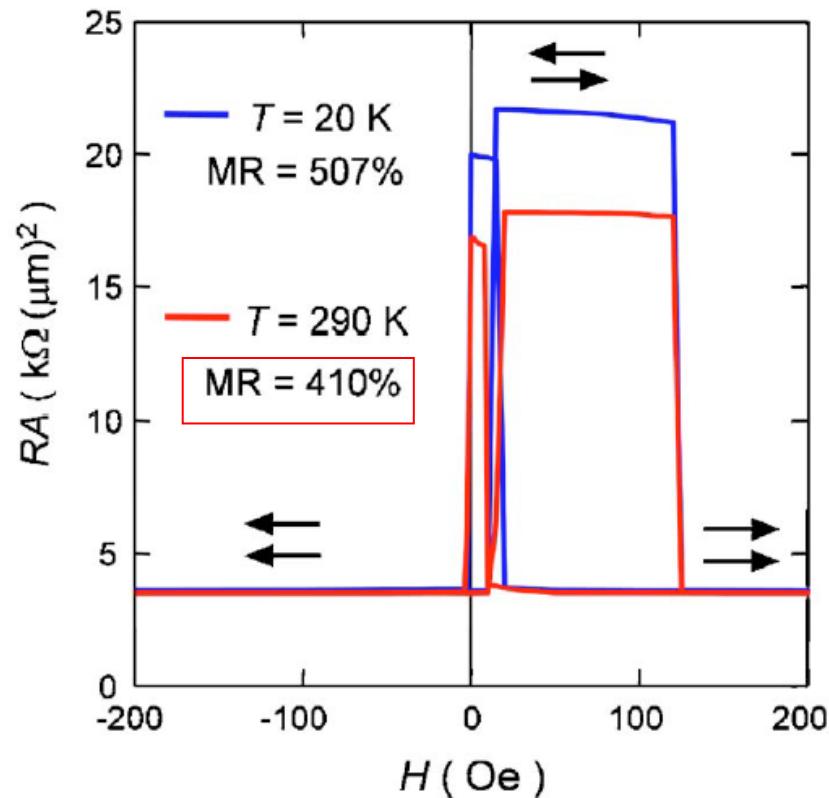
S.Yuasa et al, *Nature Mat.* (2004), *nmat 1257*.

Very well textured MgO barriers grown by sputtering or MBE on bcc CoFe or Fe magnetic electrodes, or on amorphous CoFeB electrodes followed by annealing to recrystallize the electrode.



Yuasa et al, *APL89*,  
042505(2006)

Au cap 50 nm
Ir-Mn 10 nm
Fe(001) 10 nm
Co(001) 0.57 nm
MgO(001) 2.2 nm
Co(001) 0.57 nm
Fe(001) 100 nm
MgO(001) 20 nm
MgO(001) sub.



## Tunneling through crystalline MgO barriers (cont'd)

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Co|MgO|Co and CoFe|MgO|CoFe were predicted to show extremely high TMR for well ordered interfaces (W.Butler, Phys.Rev.B.(2000)).

New mechanism of spin-filtering during tunneling through MgO according to symmetry of wave functions.

Spin alignment	up-up	down-down	up-down or down=up	$G_P/G_{AP}$
Fe MgO Fe	$2.55 \times 10^9$	$7.08 \times 10^7$	$2.41 \times 10^7$	<b>54.3</b>
Co MgO Co	$8.62 \times 10^8$	$7.51 \times 10^7$	$3.60 \times 10^6$	<b>147.2</b>
FeCo MgO FeCo	$1.19 \times 10^9$	$2.55 \times 10^6$	$1.74 \times 10^6$	<b>353.5</b>

The conductances above were calculated by integrating over the entire Fermi surface. They assumed 8 layers of MgO.

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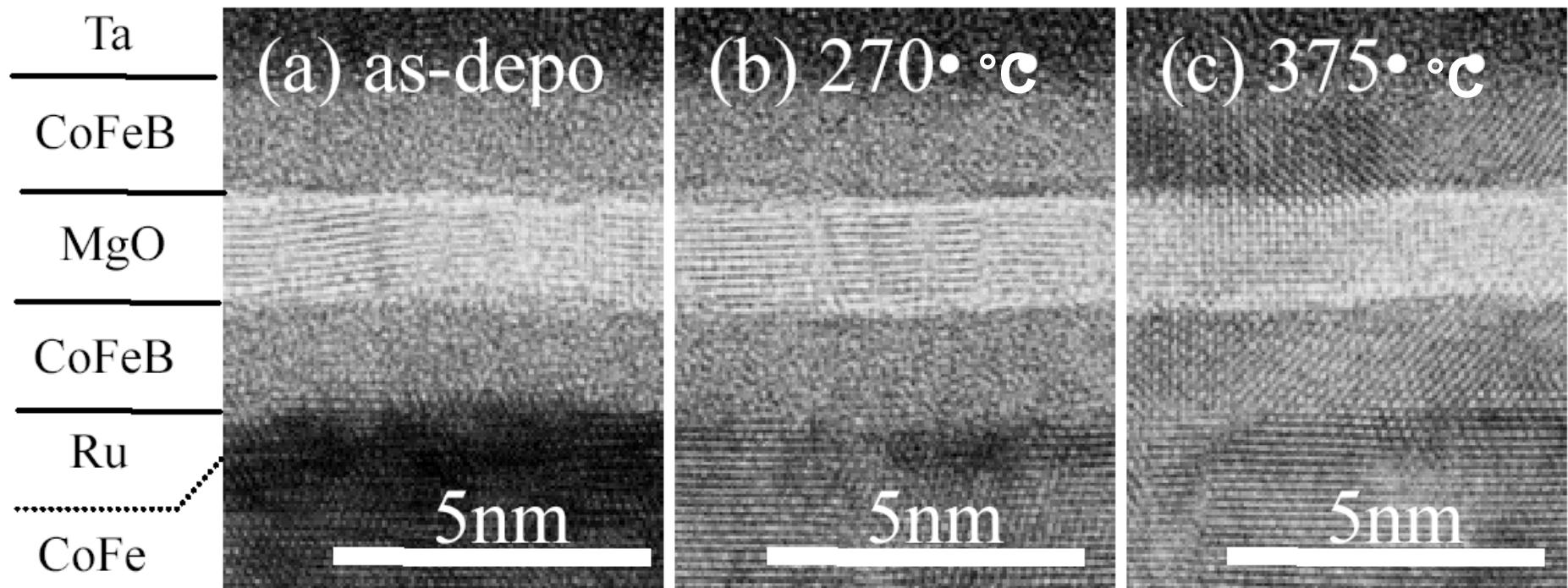
*W.Butler, Alabama Univ*

## Magnetic tunnel junctions based on MgO tunnel barriers

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- As-deposited, CoFeB amorphous, MgO polycrystalline
- Upon annealing, recrystallization of CoFeB from the MgO interfaces and improvement in MgO crystallinity with (100) bcc texture

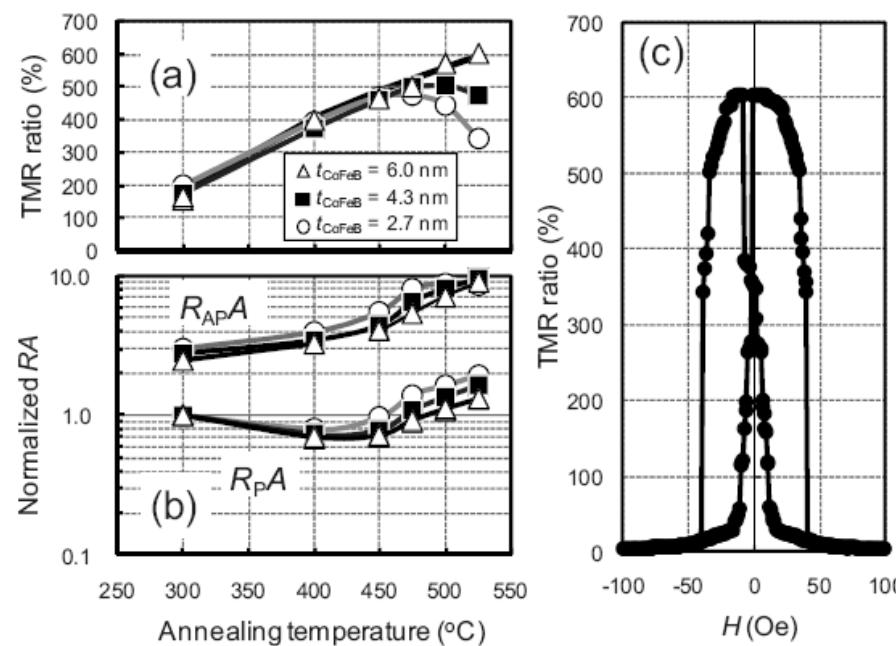
*J. Hayakawa et al. Jap. J. Appl. Physics 2005*



*Also, Yuasa et al. Applied Physics Letters, 2005*

# Tunnel magnetoresistance of 604% at 300 K by suppression of Ta diffusion in CoFeB/MgO/CoFeB pseudo-spin-valves annealed at high temperature

S. Ikeda,<sup>1,a)</sup> J. Hayakawa,<sup>2</sup> Y. Ashizawa,<sup>3,b)</sup> Y. M. Lee,<sup>1,c)</sup> K. Miura,<sup>1,2</sup> H. Hasegawa,<sup>1,2</sup> M. Tsunoda,<sup>3</sup> F. Matsukura,<sup>1</sup> and H. Ohno<sup>1,d)</sup>



Applied Physics Express 2 (2009) 083002

## Large Tunnel Magnetoresistance of 1056% at Room Temperature in MgO Based Double Barrier Magnetic Tunnel Junction

Lixian Jiang, Hiroshi Naganuma\*, Mikihiko Oogane, and Yasuo Ando

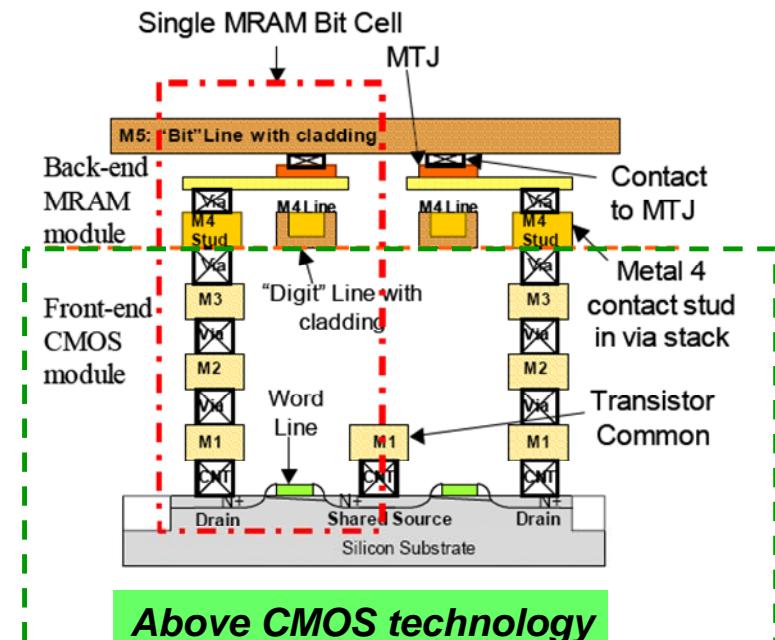
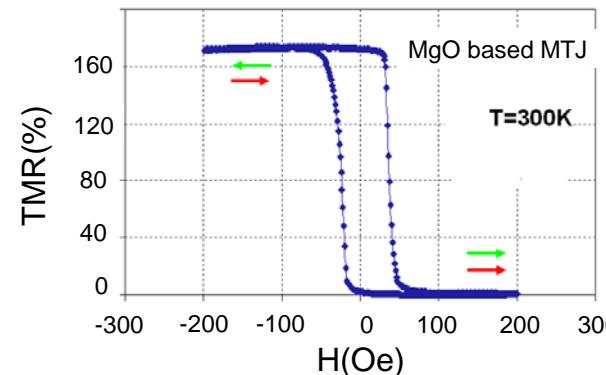
Department of Applied Physics, Graduate School of Engineering, Tohoku University, Aoba, Aramaki, Aoba-ku, Sendai 980-8579, Japan

Received June 29, 2009; accepted July 2, 2009; published online July 17, 2009

# Magnetic Tunnel Junctions (MTJ): a reliable path for CMOS/magnetic integration



- Resistance of MTJ compatible with resistance of passing FET (few  $k\Omega$ )
- MTJ can be deposited in magnetic back end process
- No CMOS contamination
- MTJ used as variable resistance controlled by field or current/voltage (Spin-transfer)
- Commercial CMOS/MTJ products available from EVERSPIN since 2006 (4Mbit MRAM)  
Implemented in Airbus flight controller



Cross-section of Freescale (Everspin)  
4Mbit MRAM based on field switching

# Spin-transfer

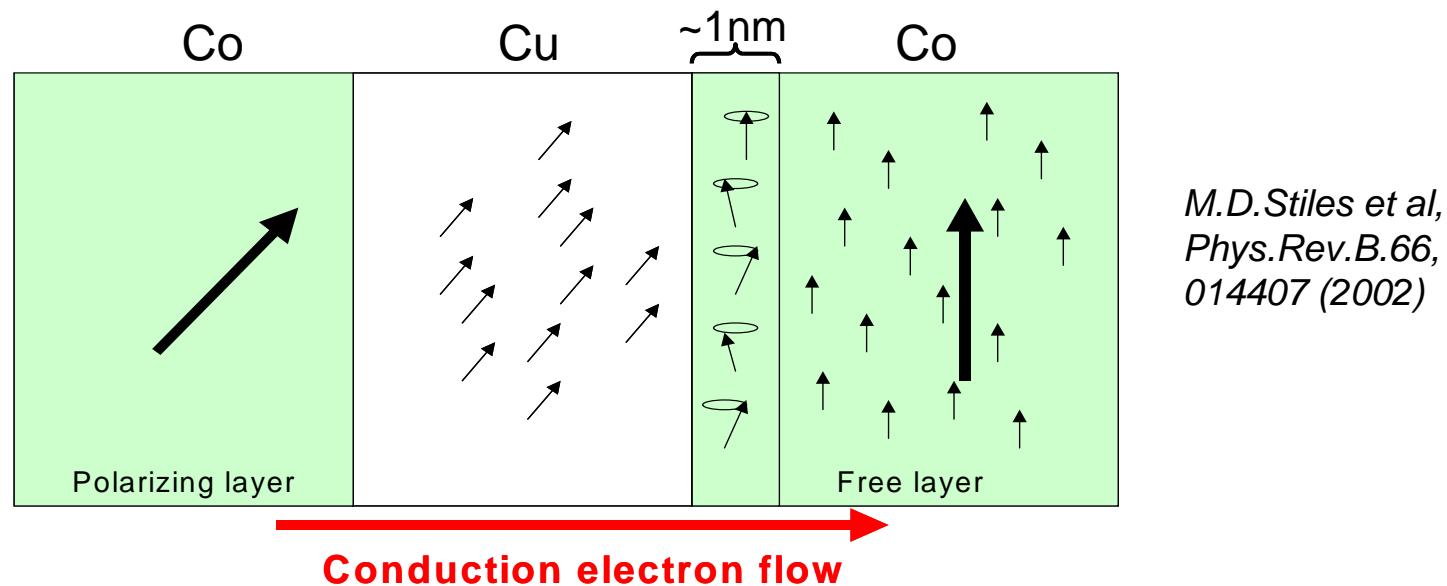
Predicted by Slonczewski (JMMM.159, L1(1996)) and Berger (Phys.Rev.B54, 9359 (1996))

## Giant or Tunnel magnetoresistance:

Acting on electrical current via the magnetization orientation

## Spin transfer is the reciprocal effect:

Acting on the magnetization via the spin polarized current



Reorientation of the direction of polarization of current via incoherent precession/relaxation of the electron spin around the local exchange field

⇒

Torque on the free layer magnetization

# Magnetization dynamics: Effective field + spin-torque

Slonczewski (JMMM.159, L1(1996)) and Berger (Phys.Rev.B54, 9359 (1996)), Stiles, Levy, Fert, Barnas, Vedyayev

$$\frac{dM}{dt} = -\gamma M \times (H_{eff} + bI.M_p) + \gamma a I.M \times (M \times M_p) + \alpha M \times \frac{dM}{dt}$$

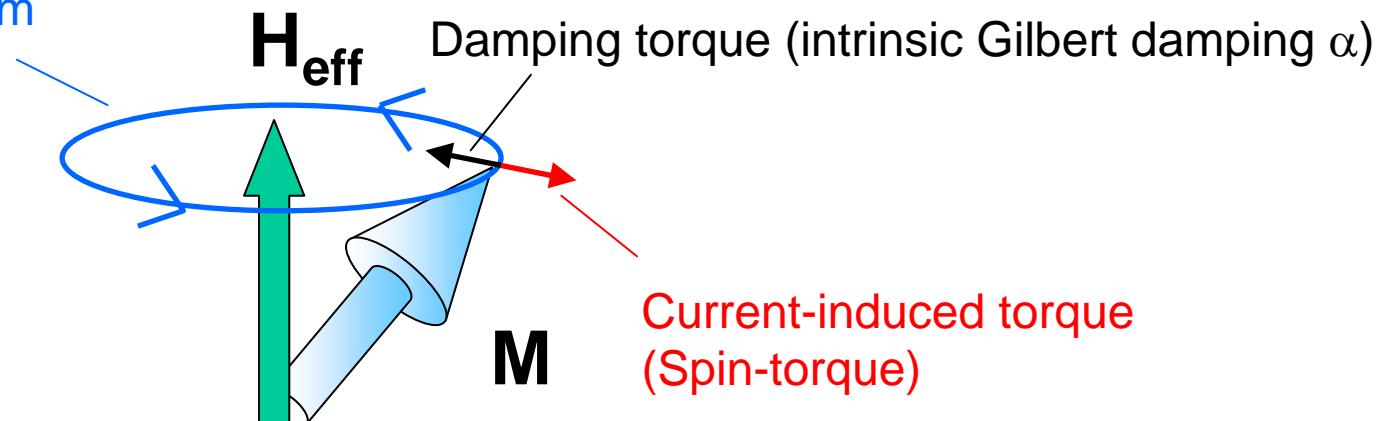
Effective field term  
(conserves energy)
Spin-torque term:  
damping  
(or antidamping) term
Polarizer  $M$

Gilbert  
Damping term  
Non conservative

( Modified LLG)

a and b are coefficients proportional to the spin polarization of the current

Precession from  
effective field



Effective field term is relatively weak in metallic pillars (<10% of spin-torque term) but more important in MTJ (~30% of spin-torque term)

# Energy dissipation and energy pumping due to spin transfer torque

Without spin torque (standard LLG)

$$\frac{dE}{dt} = -\frac{\alpha\gamma}{1+\alpha^2} \frac{1}{M_s} |\mathbf{H}_{eff} \times \mathbf{M}|^2 < 0$$

Dissipation, leading to relaxation towards effective field

Z.Li and S.Zhang,  
Phys.Rev.B68, 024404 (2003)

With spin torque term :

$$\frac{dE}{dt} = -\frac{\gamma}{1+\alpha^2} \frac{1}{M_s} [\alpha |\mathbf{H}_{eff} \times \mathbf{M}|^2 - a_J (\alpha M_s \hat{\mathbf{M}}_p - \mathbf{M} \times \hat{\mathbf{M}}_p) \times (\mathbf{H}_{eff} \times \mathbf{M})],$$

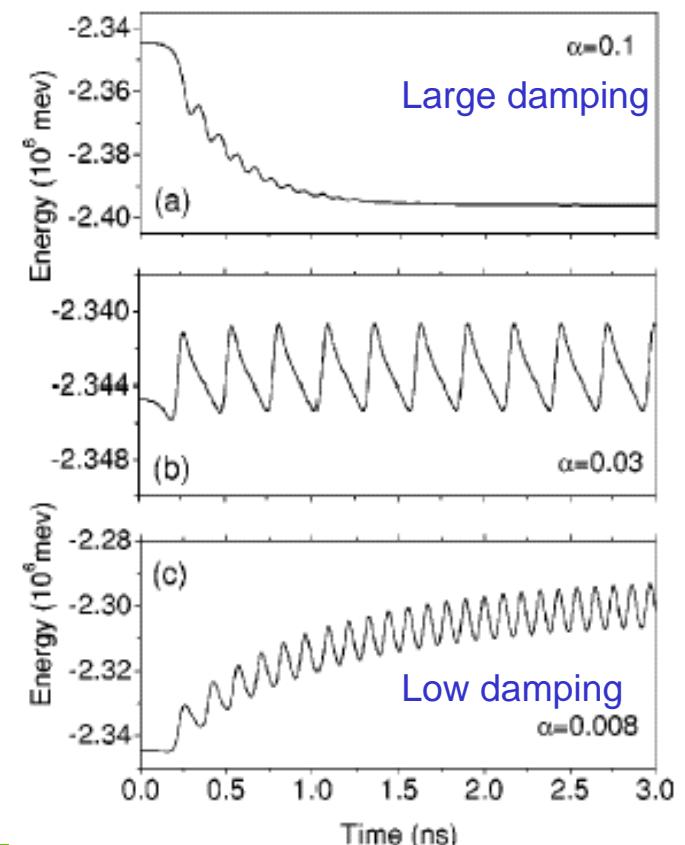
Proportional to current

$dE/dt$  can be either  $>0$  or  $<0$

With large damping: standard dynamical behavior,

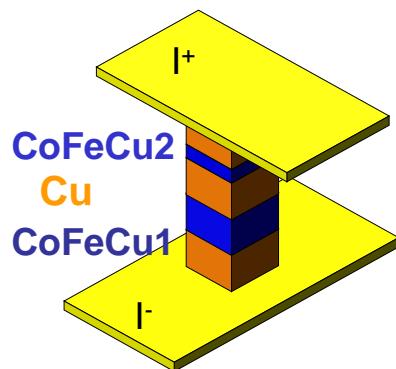
With low damping: New dynamical effects such as spin current induced steady excitations.

**The magnetization pumps energy from the spin-current.**

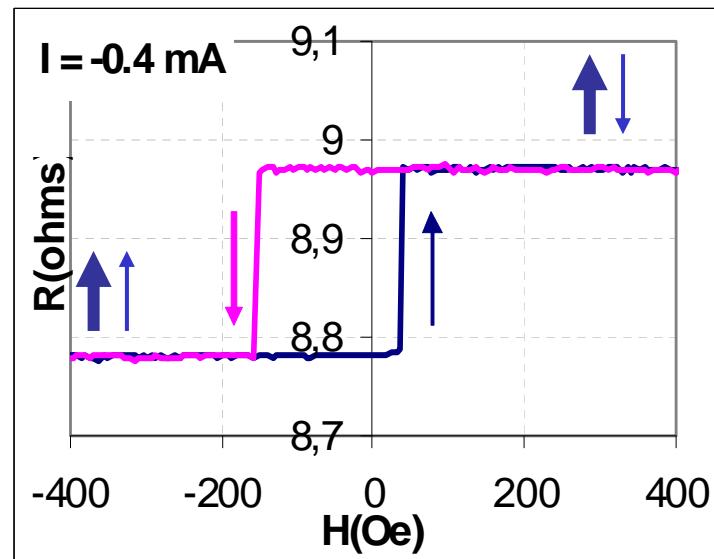


# Magnetization switching induced by a polarized current

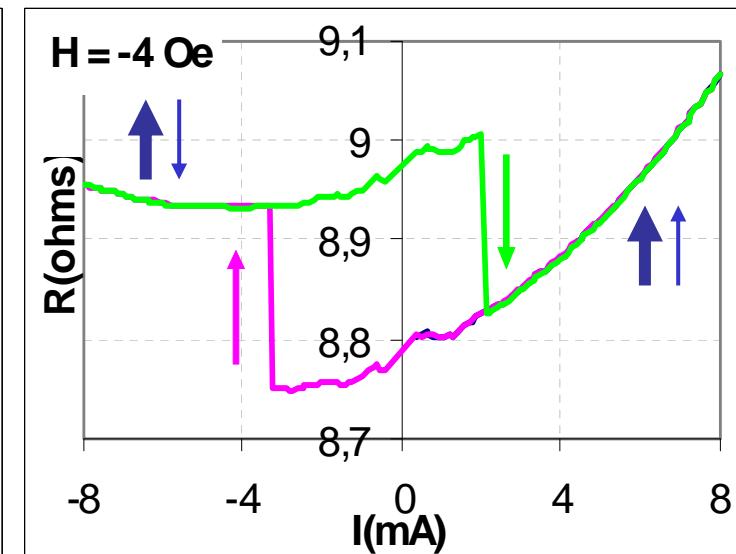
Katine et al, Phys.Rev.Lett.84, 3149 (2000) on Co/Cu/Co sandwiches ( $J_c \sim 2-4.10^7 A/cm^2$ )



Field scan



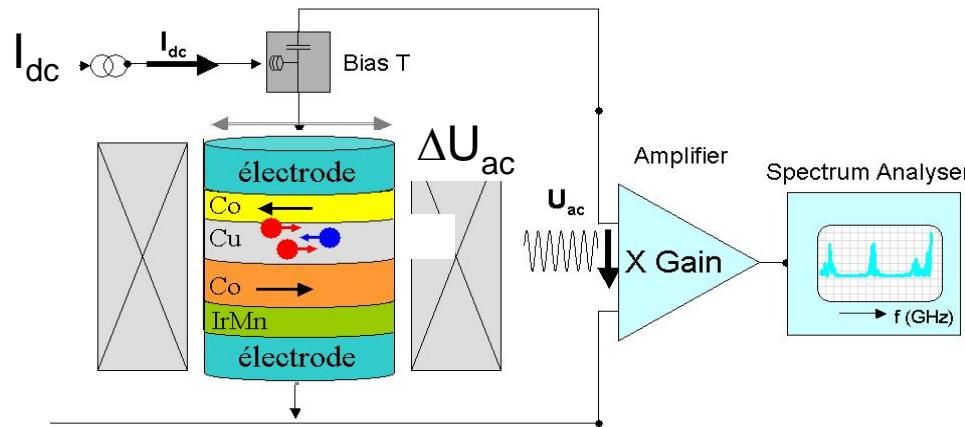
Current scan



$$j_c^{P-AP} = 1.9 \cdot 10^7 A/cm^2$$
$$j_c^{AP-P} = 1.2 \cdot 10^7 A/cm^2$$

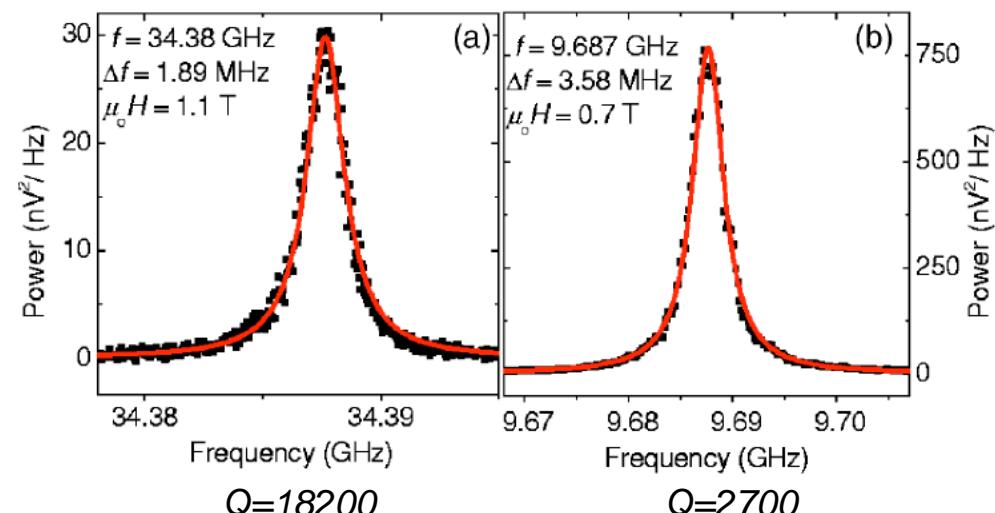
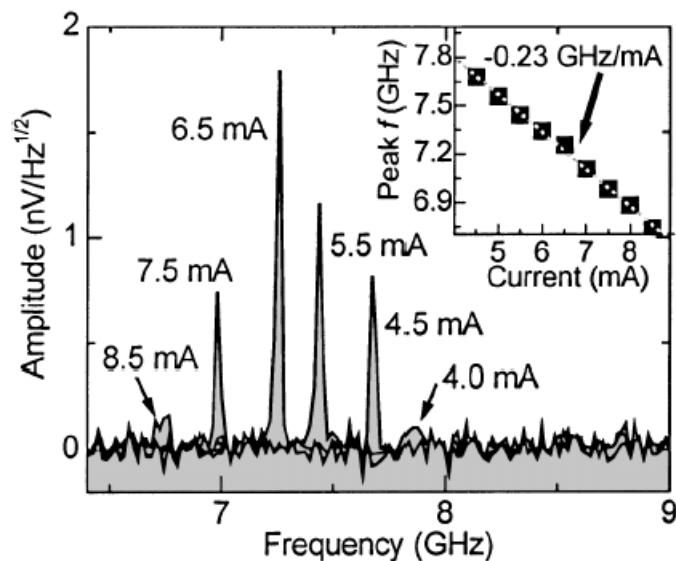
By spin transfer, a spin-polarized current can be used to manipulate the magnetization of magnetic nanostructures instead of by magnetic field.  
⇒ Can be used as a **new write scheme in MRAM**  
⇒ Or to generate steady state oscillations leading to **RF oscillators**

# Steady magnetic excitations induced by a polarized current



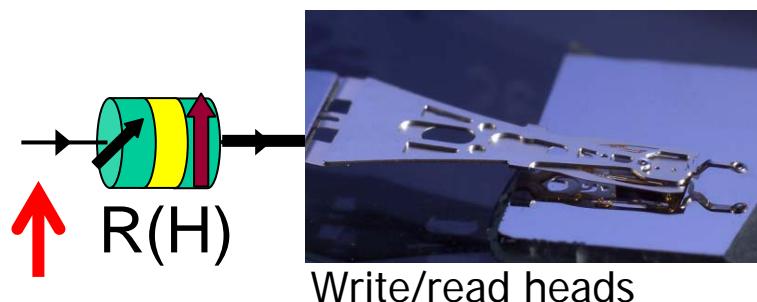
Kiselev et. al.,  
*Nature* **425**,  
p. 380 (2003)

Rippard et. al.,  
*Phys. Rev. Lett.* **92**,  
p. 27201 (2004)

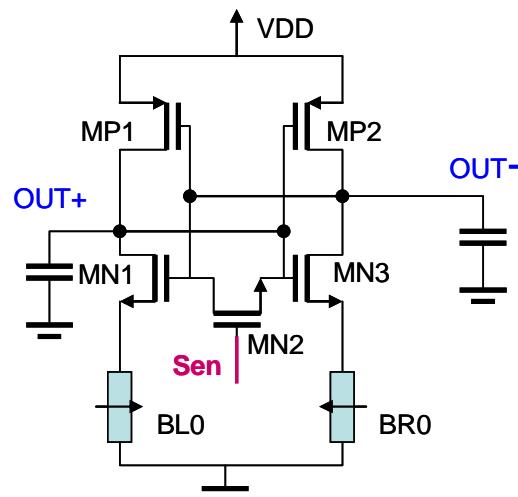


Interesting for RF components

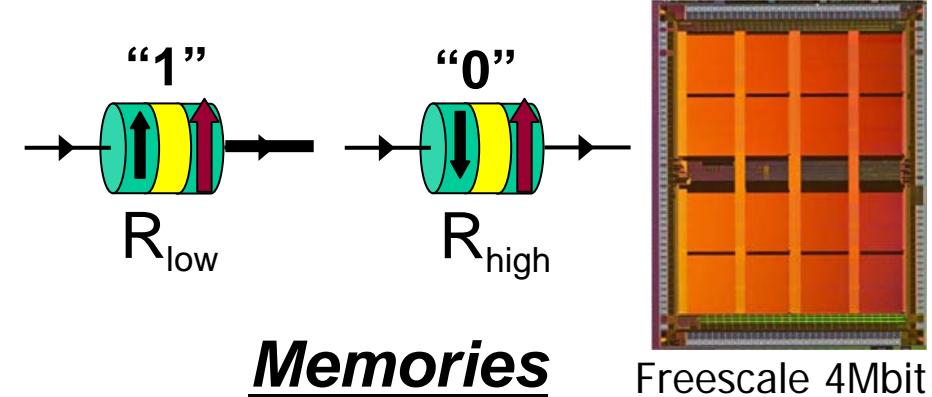
# Spintronic components



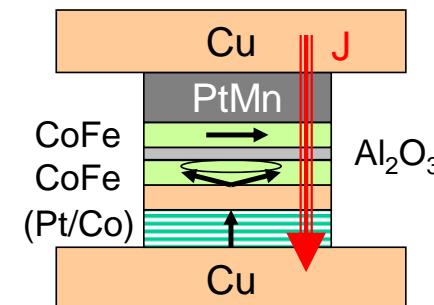
## Magnetic field sensors



## Logic circuits



## Memories

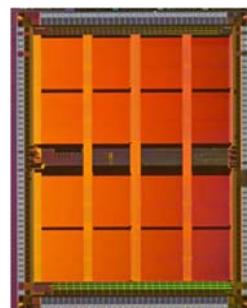
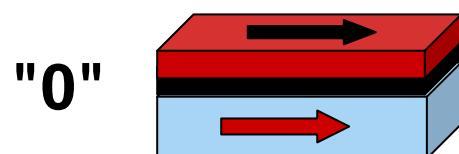
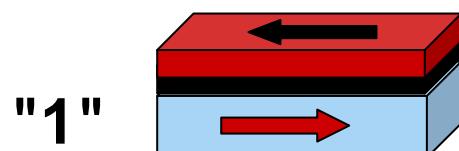


## RF components

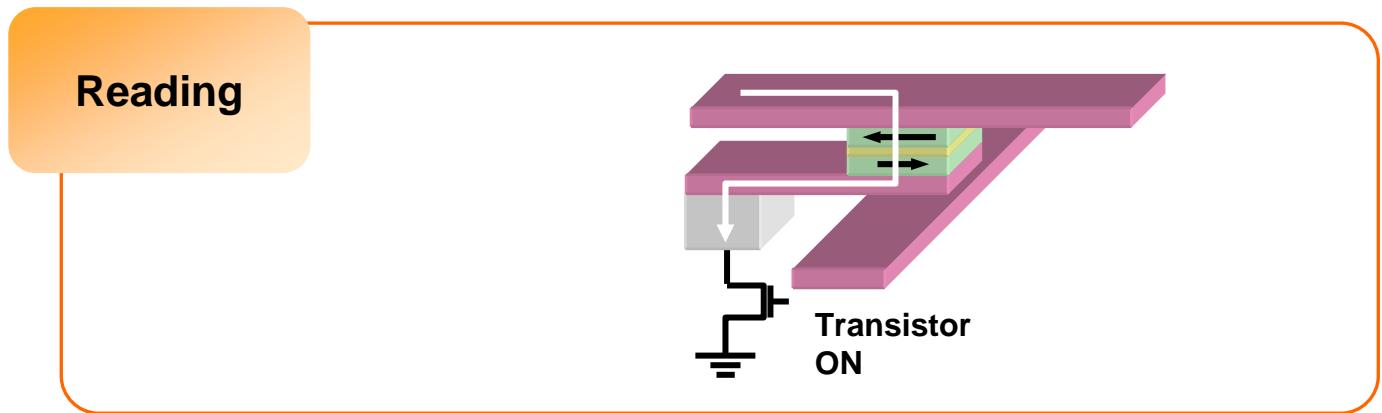
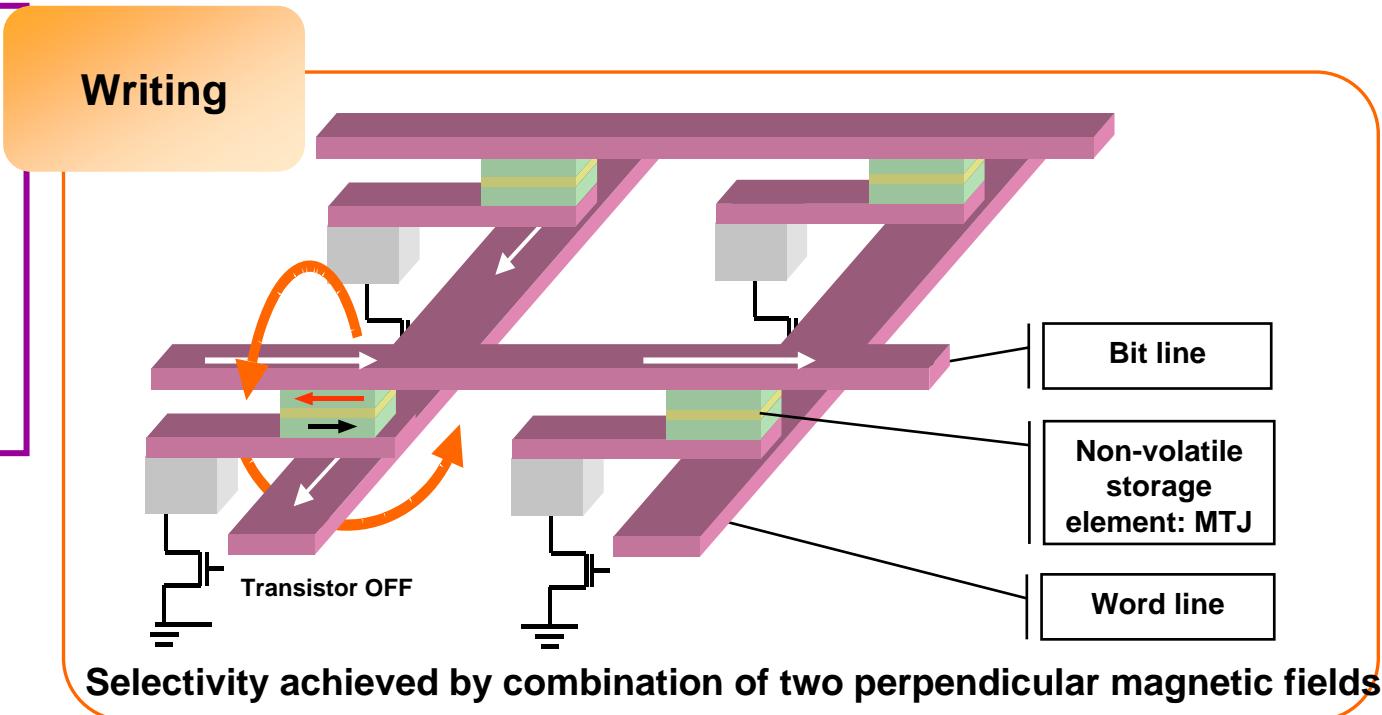
# Field induced magnetic switching (FIMS) MRAM

## Principle :

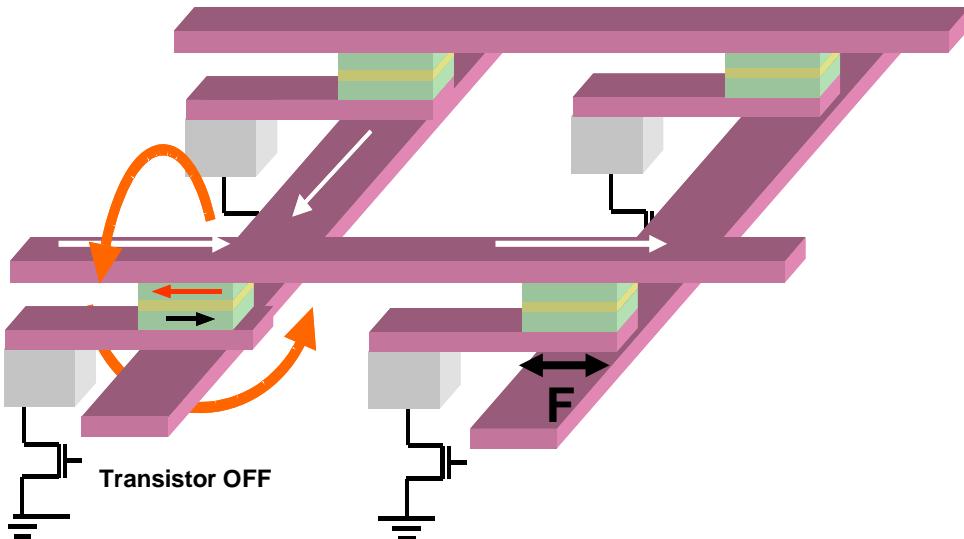
Store data by the direction (parallel or antiparallel) of magnetic layers in MTJ



Freescale  
4Mbit  
(2006)



## Poor scalability of field induced switching MRAM



Limited scalability due to electromigration in bit/word lines

Energy barrier  $KV > 40k_B T$  required for thermal stability of the information,

if  $V \downarrow \sim F^2$ , then  $K$  and  $H_{\text{write}} \uparrow \sim 1/F^2$

$H_{\text{write}}$  in the range 5mT-10mT requiring write current  $\sim 5-10\text{mA}$

As a result,  $I_{\text{write}} \uparrow \sim 1/F^2$  so that current density  $j_{\text{write}} \uparrow > 1/F^3$

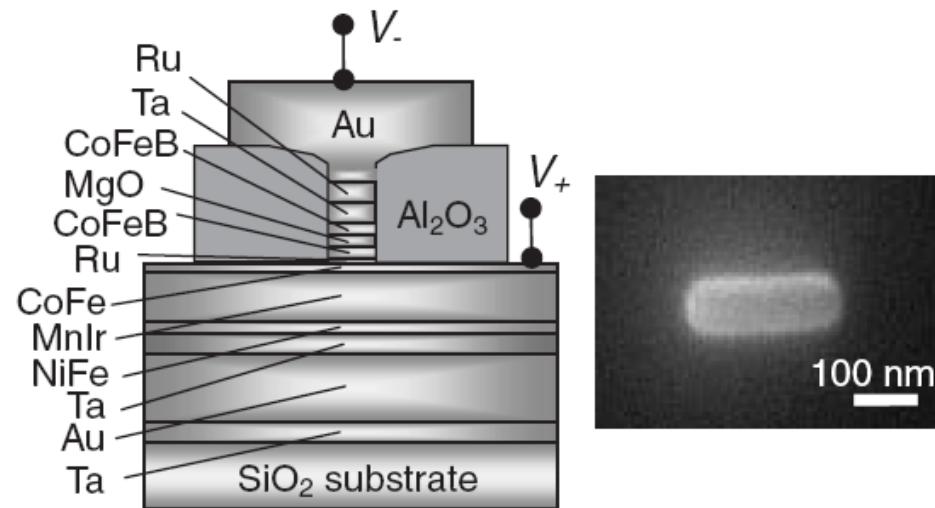
Electromigration limit:  $j_{\text{max}} \sim 10^7 \text{A/cm}^2$  reached around  $F=60\text{nm}$

## Solution 1: Spin-Transfer Torque MRAM

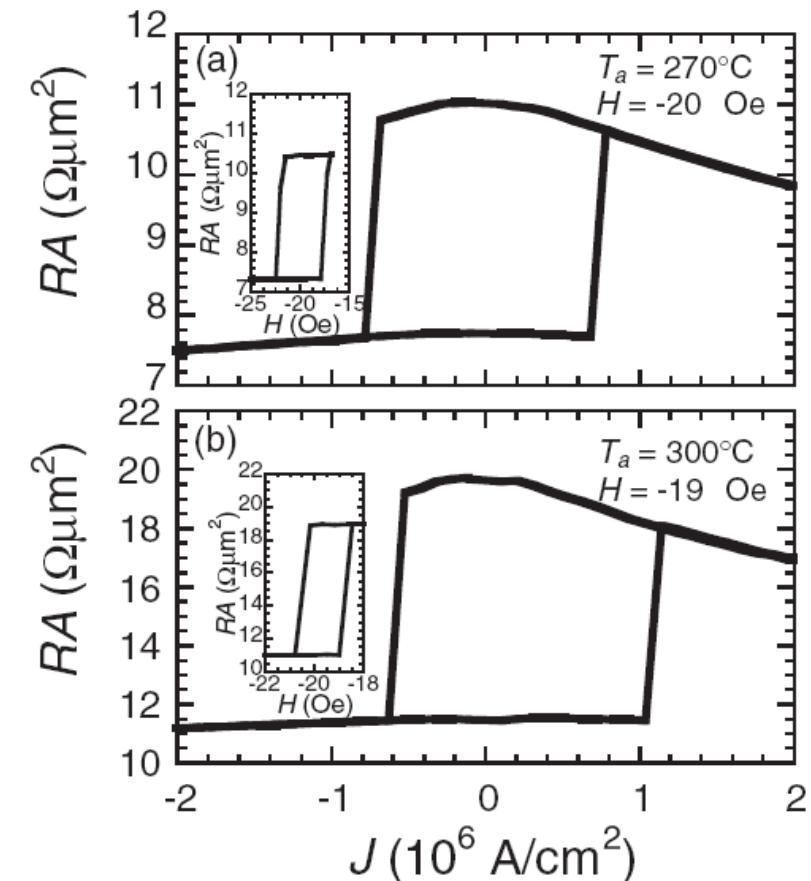
Slonczewski, Berger (1996); STT in MTJ: Huai et al, APL (2004); Fuchs et al, APL (2004)

The bipolar current flowing through the MRAM cell is used to switch the magnetization of the storage layer.

Reading at lower current density than writing so as to not perturb the written information while reading.

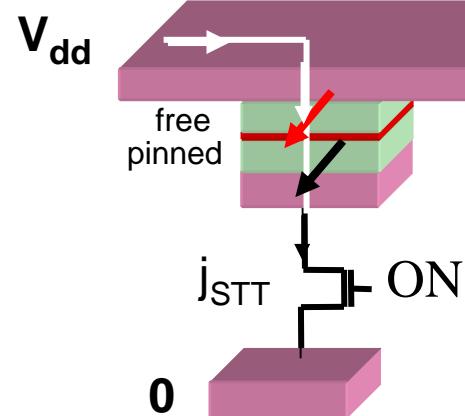


Hayakawa et al,  
Japanese Journal of Applied Physics  
44, (2005), L 1267

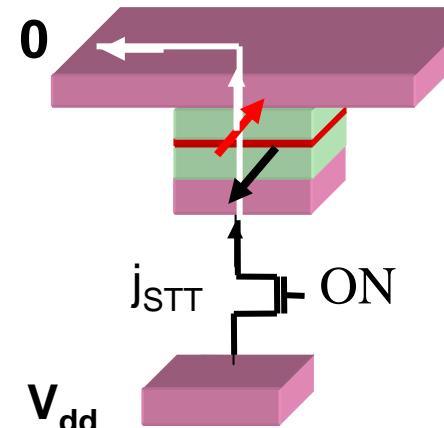


## STT MRAM scalability

Writing “0”



Writing “1”



- Writing determined by a current density :  $j_{WR \text{ in-plane}} = \left( \frac{2e}{\hbar} \right) \frac{\alpha t_F}{P} \left( \frac{\mu_0 M_s^2}{2} + 2K \right)$
- Current through cell proportional to MTJ area

$$\bullet j_{\text{write SST in-plane}} \sim 8.10^5 \text{A/cm}^2 \text{ quasistatic} \Rightarrow 3.10^6 \text{A/cm}^2 @ 10\text{ns}$$

*Huai et al, Appl.phys.Lett.87, 222510 (2005) ; Hayakawa, Jap.Journ.Appl.Phys.44 (2005) L1246*

- Still need to reduce critical current for switching by factor ~4 to minimize electrical stress on the barrier.
- Concern with thermal stability of the cell below 45nm (superparamagnetic limit)

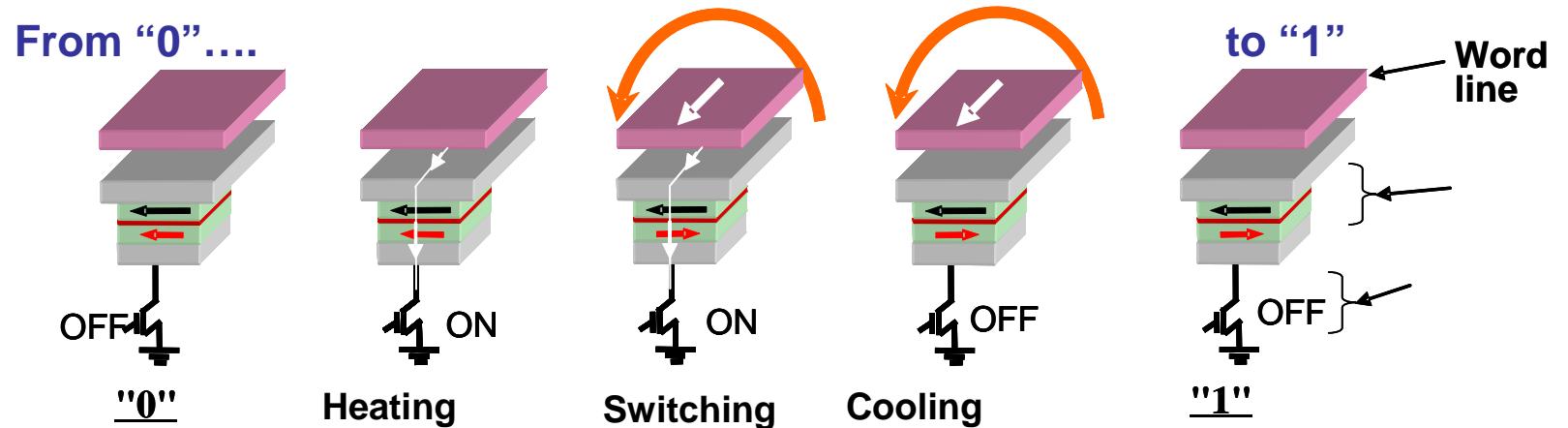
## Solution 2 : Thermally assisted MRAM

Very similar to Heat Assisted Magnetic Recording (HAMR)

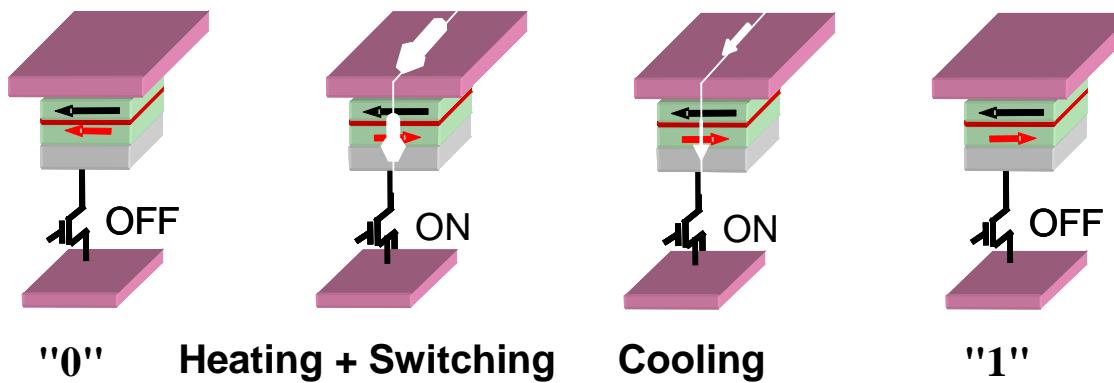
Write at elevated temperature (switching easier) – Store at room temperature

In TA-MRAM: Heating by current flowing through the cell

Heating+ pulse of magnetic field:



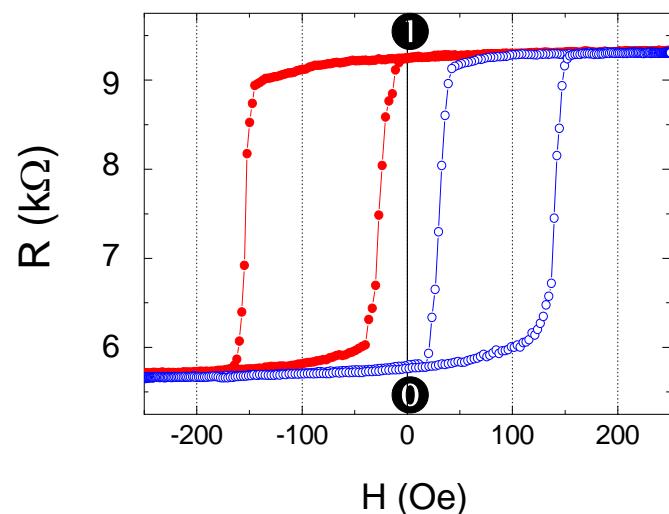
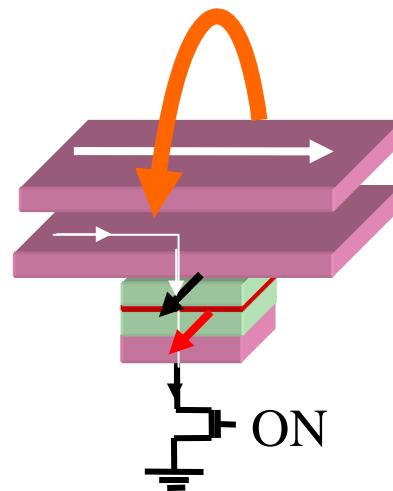
Heating + STT:



FR2832542 filed 16th Nov.2001, US6385082

# Thermally assisted writing in TA-MRAM

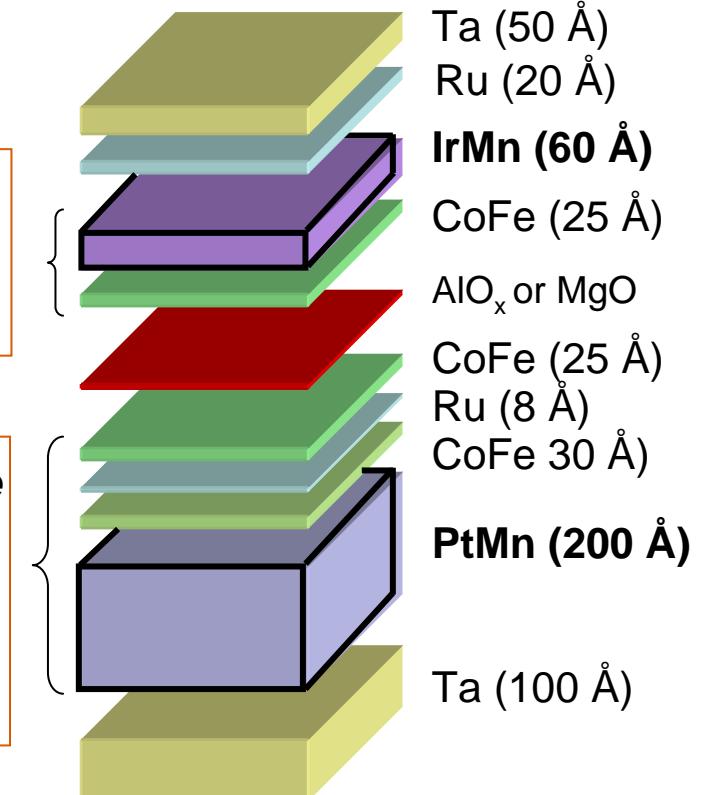
Heating  
+  
Field  $\sim 2.5\text{mT}$



## Exchange biased storage layer

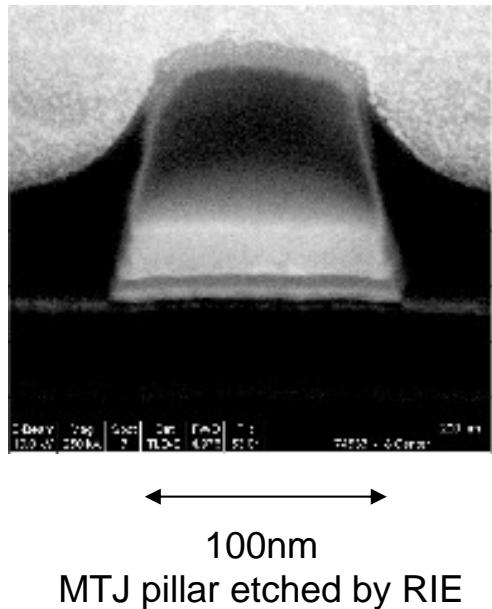
Storage  
Low  $T_B$   
 $\sim 180^\circ\text{C}$

Reference  
High  $T_B$   
 $\sim 350^\circ\text{C}$

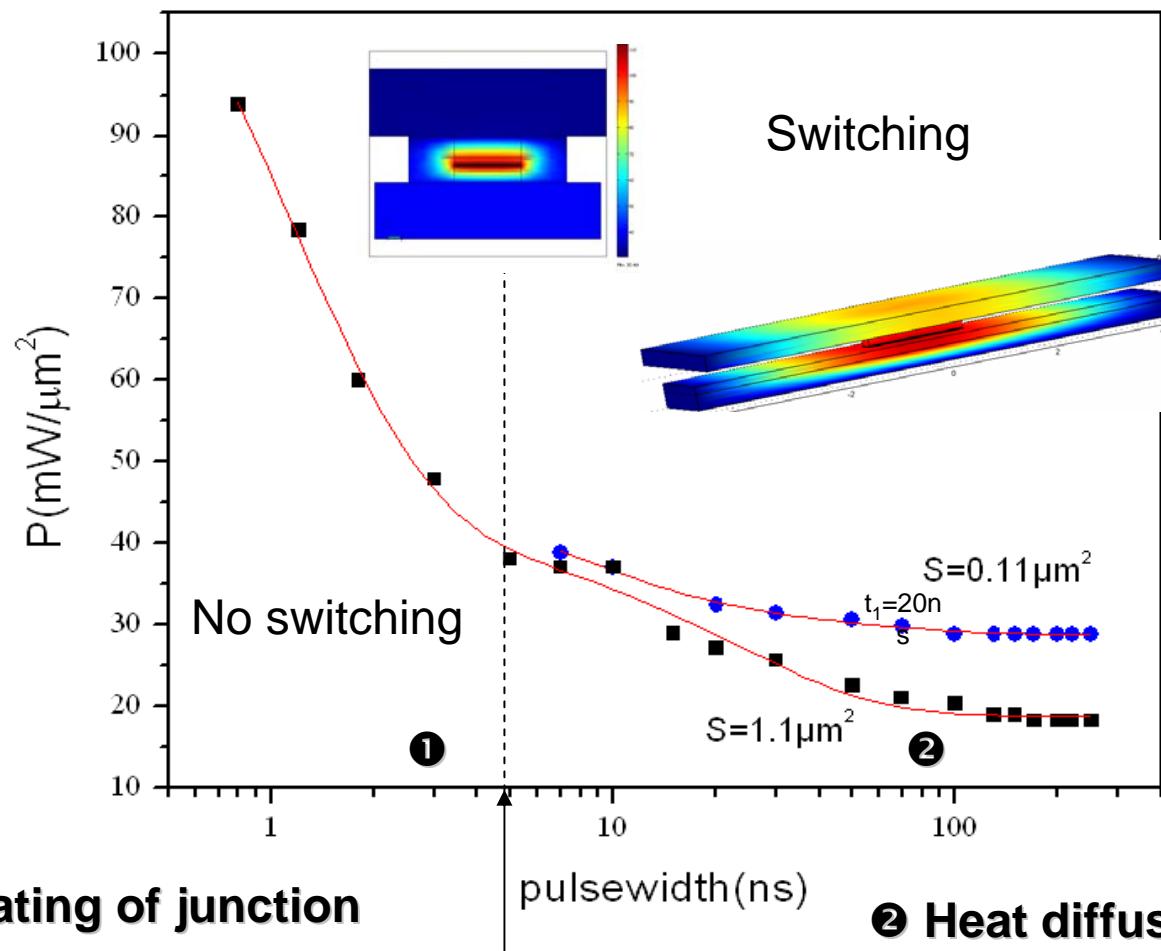


➤ heat the storage layer above the **low  $T_B$**

# Heating Dynamics in TA-MRAM



**CROCUS Technology**  
Blossoming Future



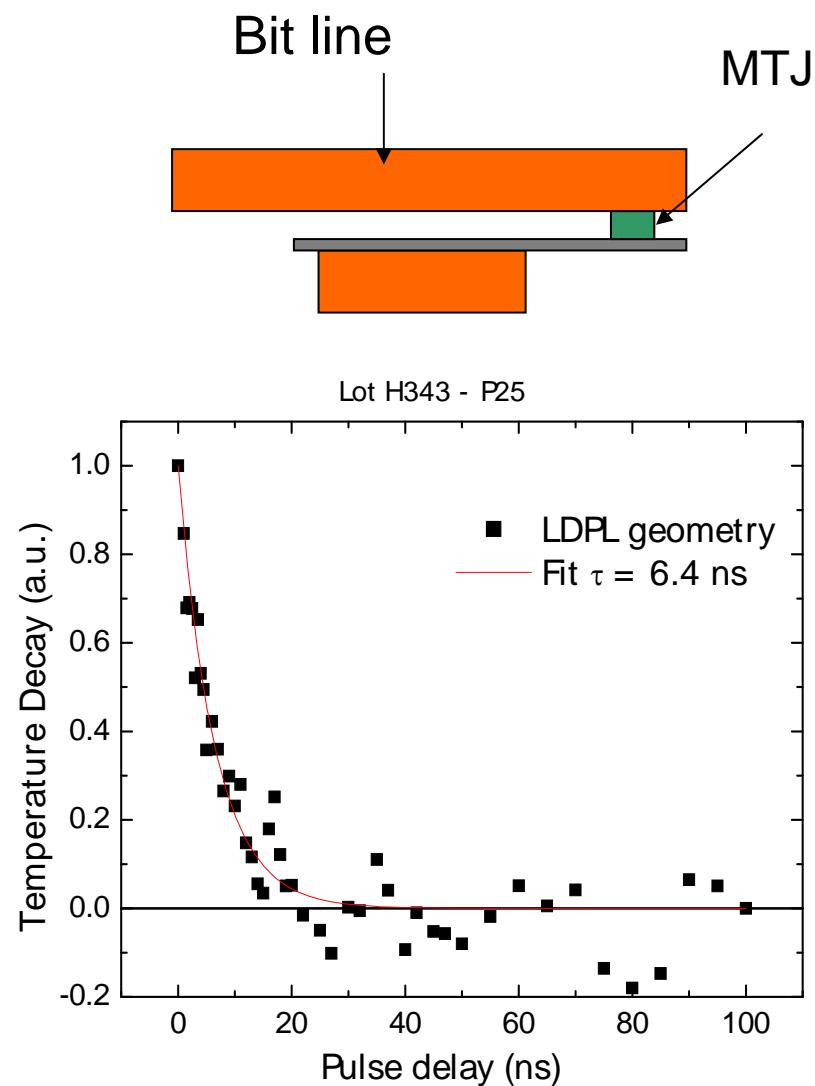
## ① Adiabatic heating of junction

$$E_{\text{write}} = C\Delta T \Rightarrow P_{\text{write}} = C\Delta T/t$$

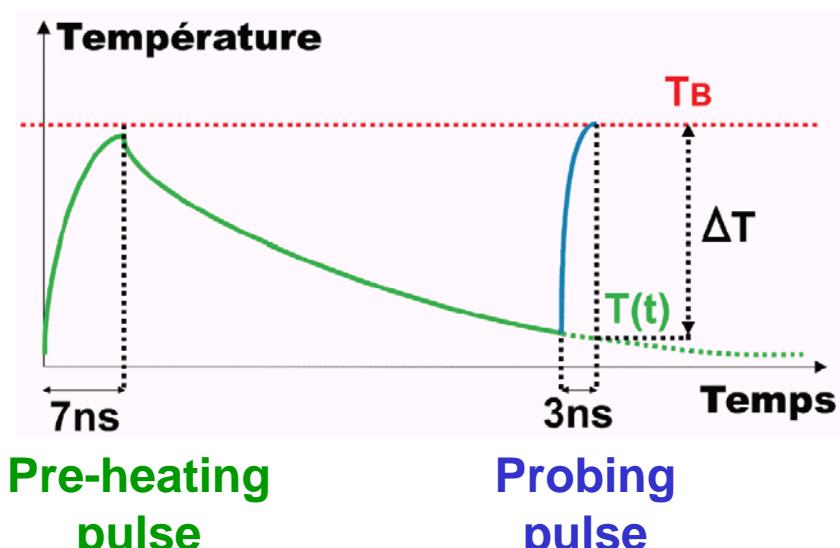
Best operating region  
 $J_{\text{heating}} \sim 10^6 \text{ A/cm}^2$

## ② Heat diffusion towards the leads

# Cooling dynamics in TA-MRAM



Double-pulse method for measuring cooling dynamics (*C.Papusoi, J.Héault*):

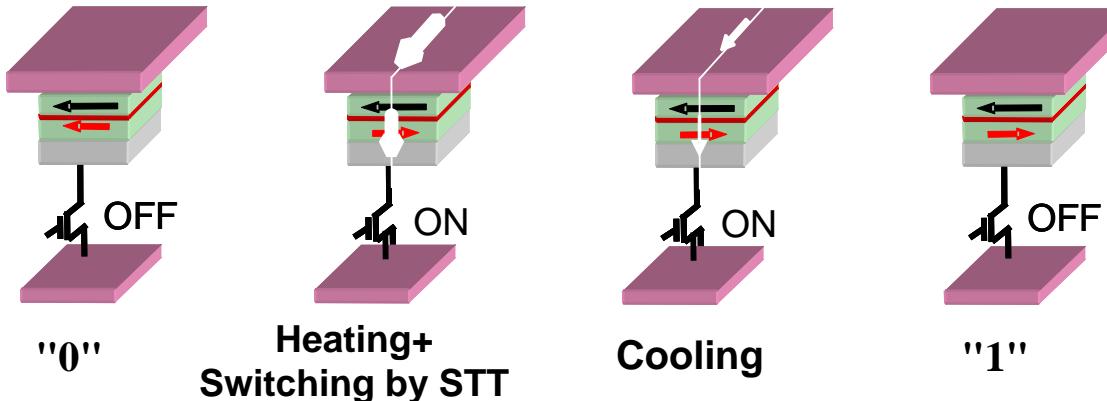


Characteristic cooling time  $\sim 15 \text{ ns}$ .

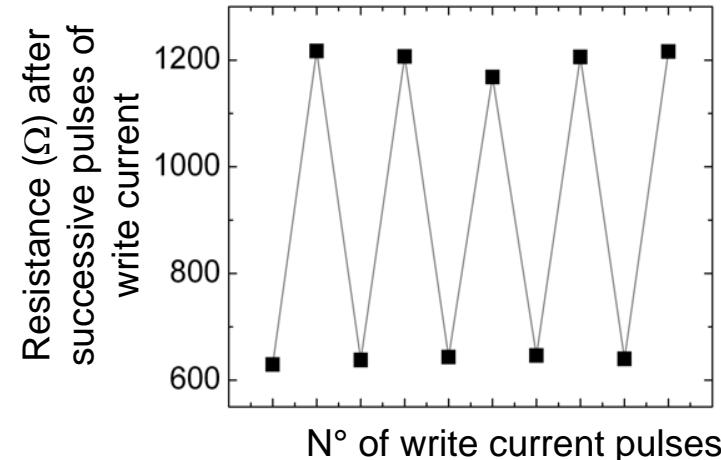
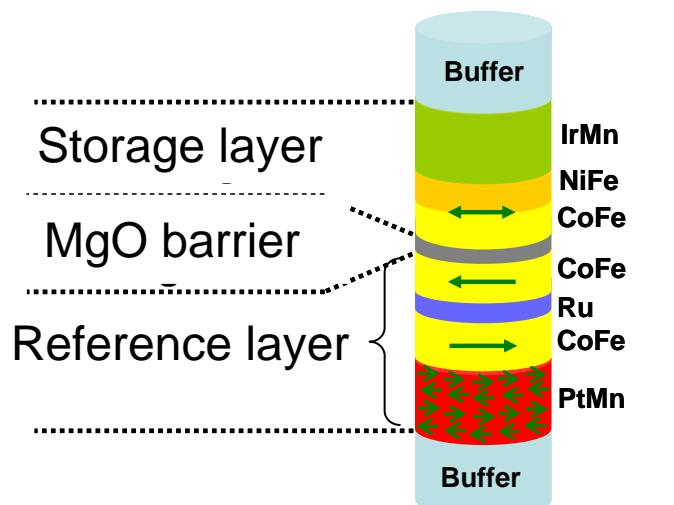
TA-MRAM cycle time  $\sim 30 \text{ ns}$

## Combining spin-transfer with thermally assisted writing

The same bipolar current flowing through the cell is used to both temporarily heat the cell and apply a spin transfer torque to switch the magnetization of the storage layer.



### Experimental demonstration:



Approach offering the ultimate scalability (sub-15nm cell-size possible) with stability of information over 10 years.

# Scalability of TA-MRAM

---

## Heating+ pulse of magnetic field~2.5mT:

Scalability limited by electromigration in bit line (field generation) @ 40nm

## Heating+ STT:

Same bipolar CPP current used to heat and switch;

No Physical limit in downscaling from magnetic point of view down to a few nm;

Can be implemented with :

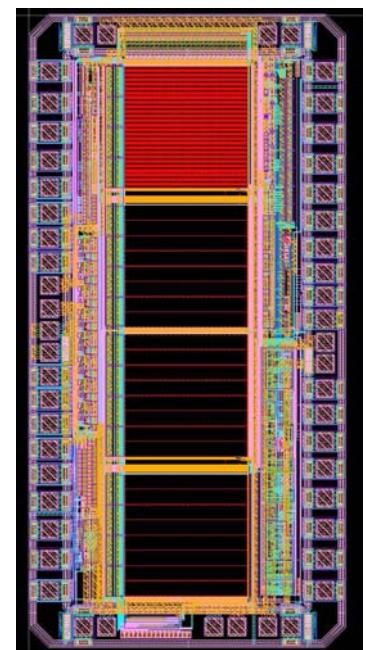
-in-plane magnetized material

(exchange biased storage layer)

-perpendicular-to-plane magnetized material

(variation of  $M_s$  or  $K$  with  $T$ )

*Layout of 1Mbit TA-MRAM demonstrator from Crocus Technology*



# Hybrid Magnetic/CMOS Integrated Electronics

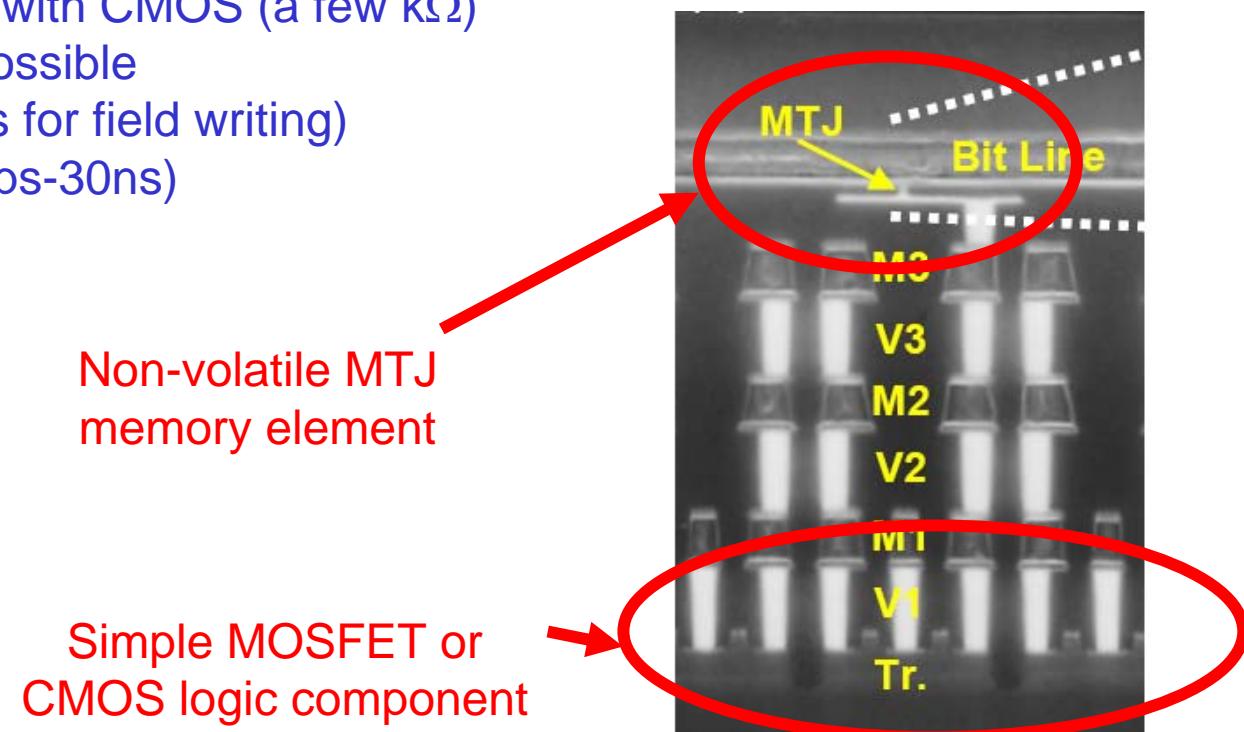
ERD-ITRS 2007:

**“Nanodevices that implement both logic and memory in the same device would revolutionize circuit and nanoarchitecture implementation”**

Possible with CMOS/MTJ integration thanks to the unique set of qualities of MTJs:

- Resistance compatible with CMOS (a few  $k\Omega$ )
- Above IC technology possible
- Cyclability ( $>10^{16}$  cycles for field writing)
- Switching speed ( $\sim 200\text{ps}-30\text{ns}$ )
- High density possible
- Thermal stability
- Radiation hardness

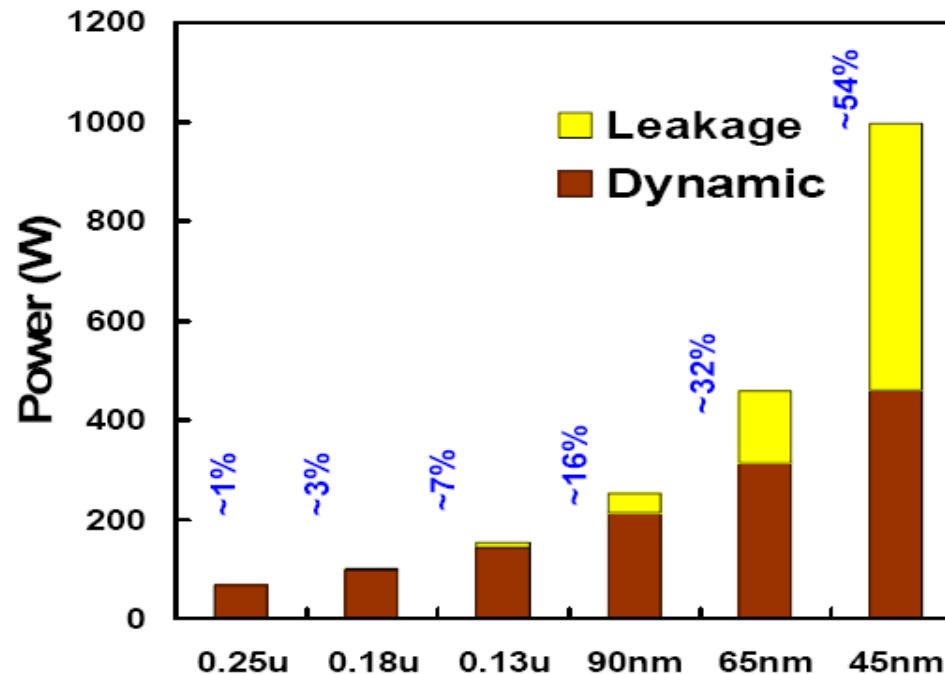
« Janus  
logic/memory  
components »



## New hybrid CMOS/MTJ architectures for non-volatile logic

DRAM, SRAM: volatile. Cannot be switched off without loosing information.  
However, increasing leakage current with downsizing (thinner gate oxide).

**Power consumption in  
CMOS electronic circuit  
per inch<sup>2</sup>**



Major benefit in introducing non-volatility in CMOS devices in terms of  
**energy savings**

## Non-volatile logic with ferroelectric RAM

---

Prototype of **non-volatile 8-bits CPU** developed by Rohm.

**Embedded FeRAM registers** to temporarily store the information;

Possibility to turn off power on the temporarily inactive parts of the processor => **50% gain in power consumption**

**Instant on restart**

However FeRam not fast enough and limited cyclability.

⇒ Advantage of MTJ's:

Speed

Cyclability (magnetic non-volatile flip-flops)

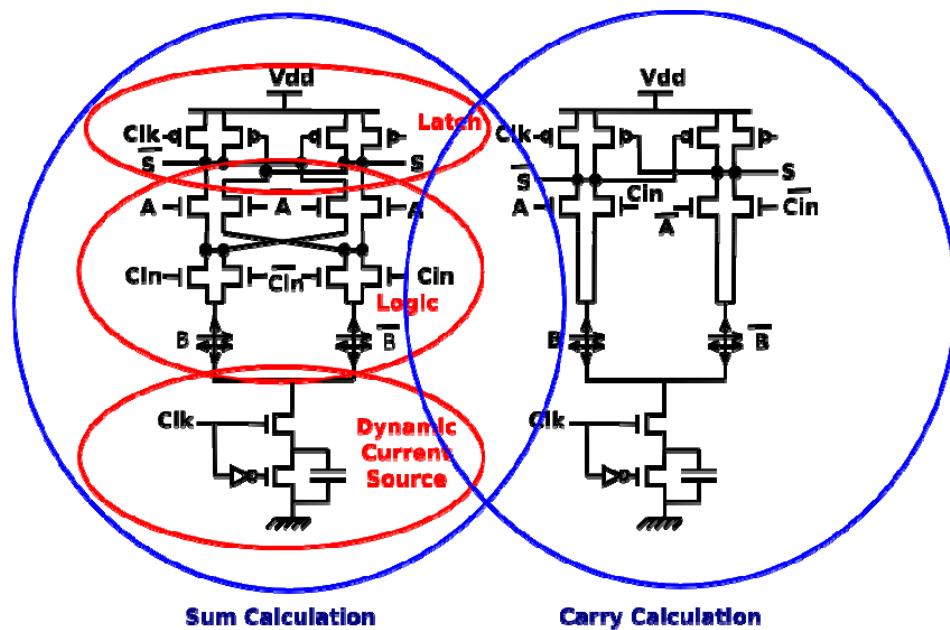


# Magnetic Full Adder (Hitachi, Tohoku University)

- Based on
  - Dynamic Current Mode Logic
  - Dynamic consumption reduction
  - Footprint reduction
- MTJs
- One input is made non-volatile (instant startup, security)
- Drastic static consumption reduction
- Footprint reduction
- Demonstrator : CMOS 0.18μm,
- MTJs size: 200X100nm<sup>2</sup>

S.Matsunaga et al, *Applied Physics Express*, vol. 1, 2008.

	CMOS	Hybrid
Delay	224 ps	219 ps
Dynamic Power	71.1 μW	16.3 μW
Writing Time	2 ns/bit	10 (2) ns/bit
Writing Energy	4 pJ/bit	20.9 (6.8) pJ/bit
Standby Power	0.9 nW	0 nW
Surface	333 μm <sup>2</sup>	315 μm <sup>2</sup>



# Tighter integration between logic and memory

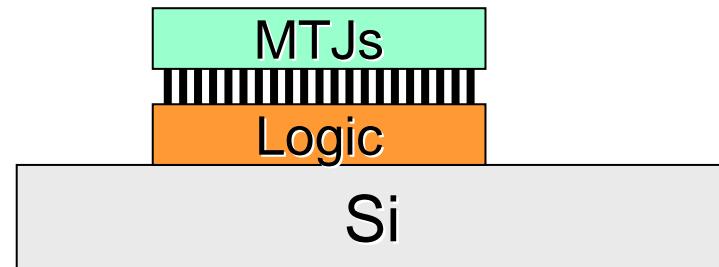
Same technology as for MRAM

Benefit from “Above IC” technology

With CMOS technology only:



With hybrid CMOS/magnetic:



- Slow communication between logic and memory
  - few long interconnections
- complexity of interconnecting paths
  - larger occupancy on wafer

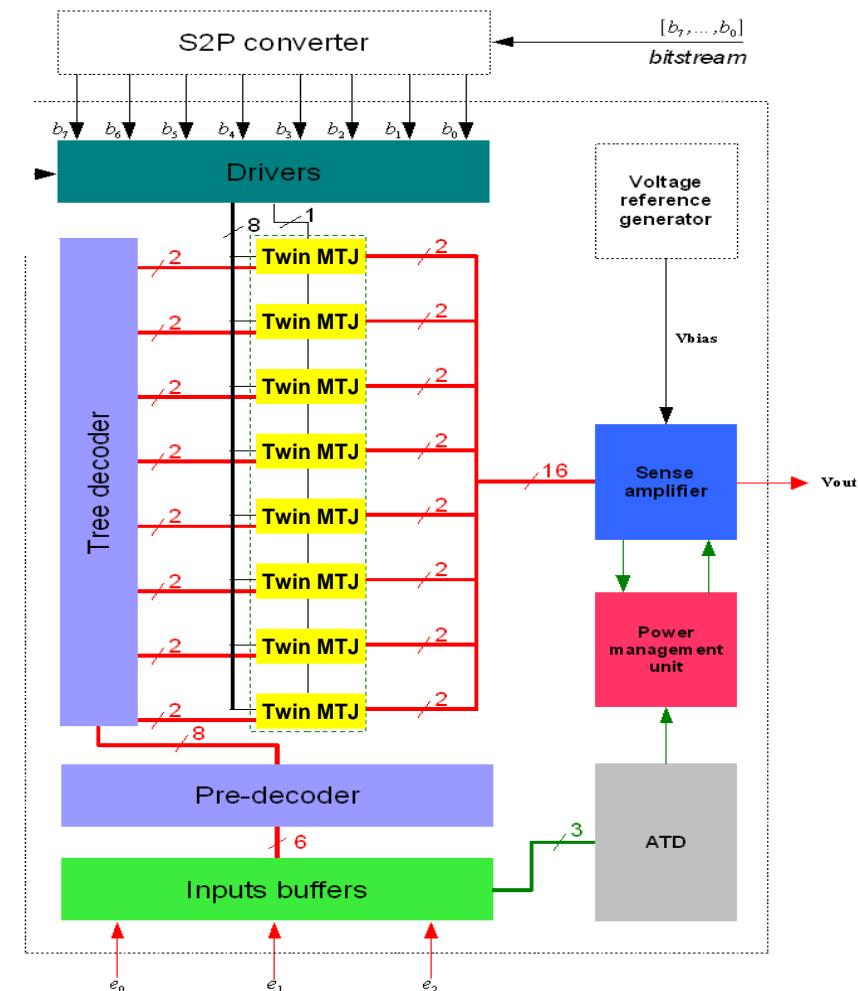
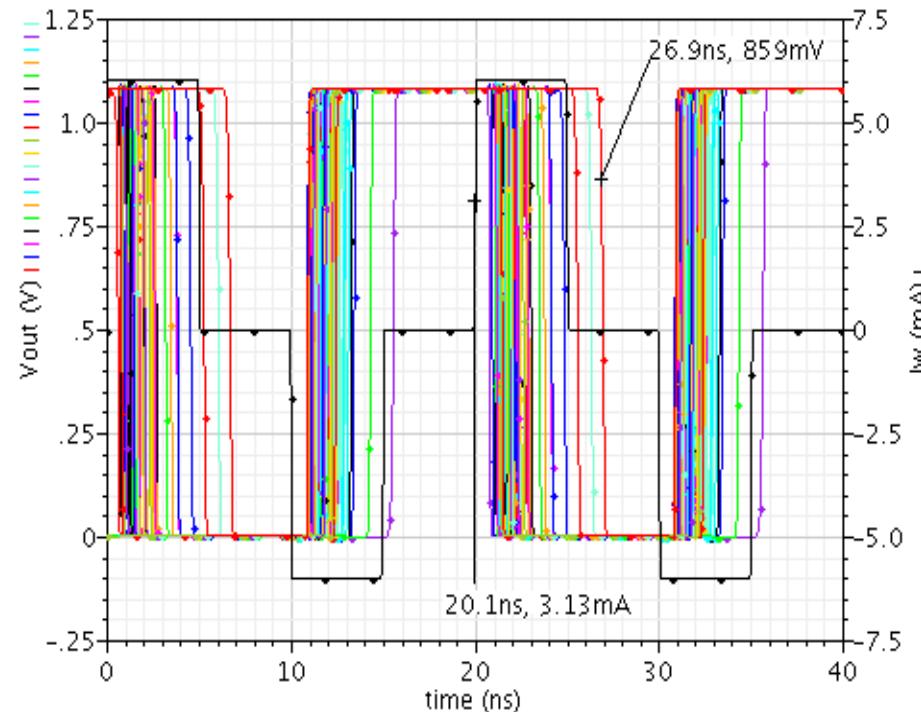
- Non-volatility in logic
- Large energy saving
- Fast communication between logic and memory
  - Numerous short vias
- Simpler interconnection paths
  - Smaller occupancy on wafer

New paradigm for architecture of complex electronic circuit (microprocessors...)

# Reprogrammable hybrid CMOS/MTJ logic gates

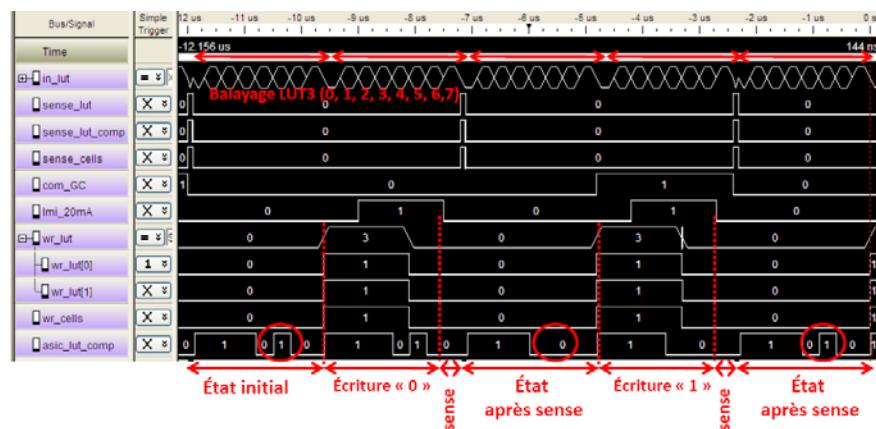
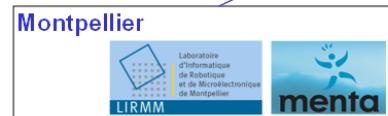
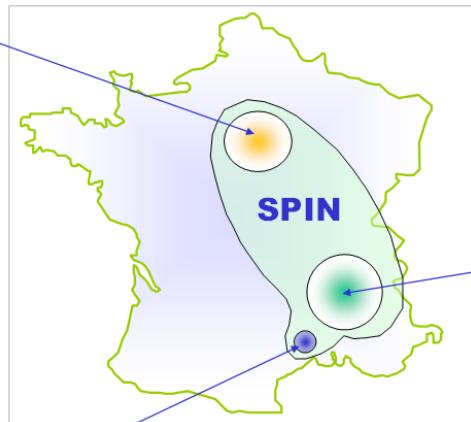
MTJ used as variable resistances to change the switching threshold of CMOS components

## Simulations of reprogrammability taking into account CMOS and magnetic process variations

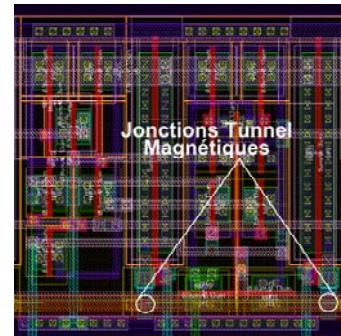


# Examples of CMOS/magnetic integrated circuits

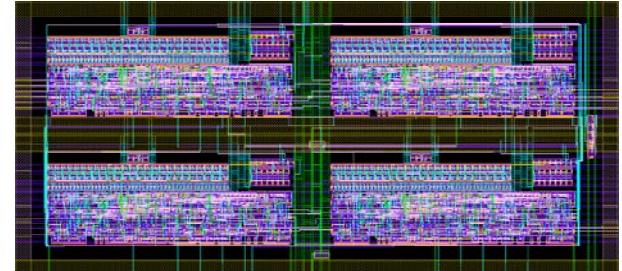
French consortium:



Non-volatile flip-flop

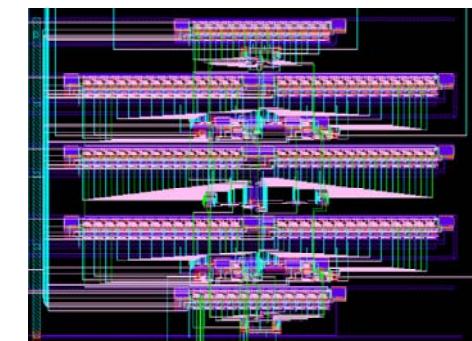
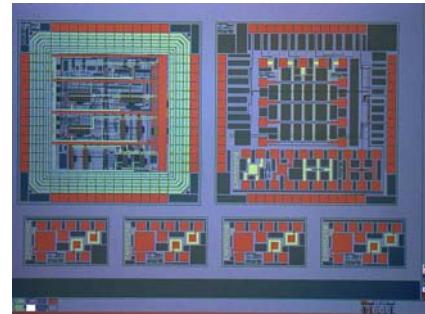


Magnetic FPGA



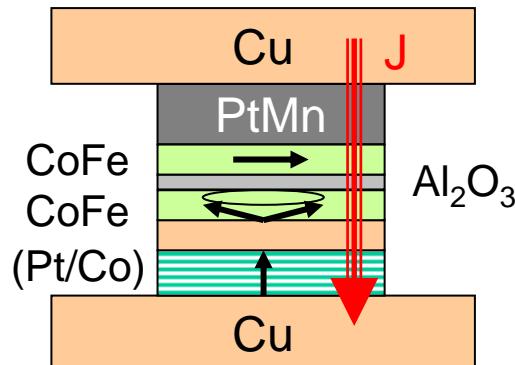
Arithmetic Logic Units

Magnetic look up table

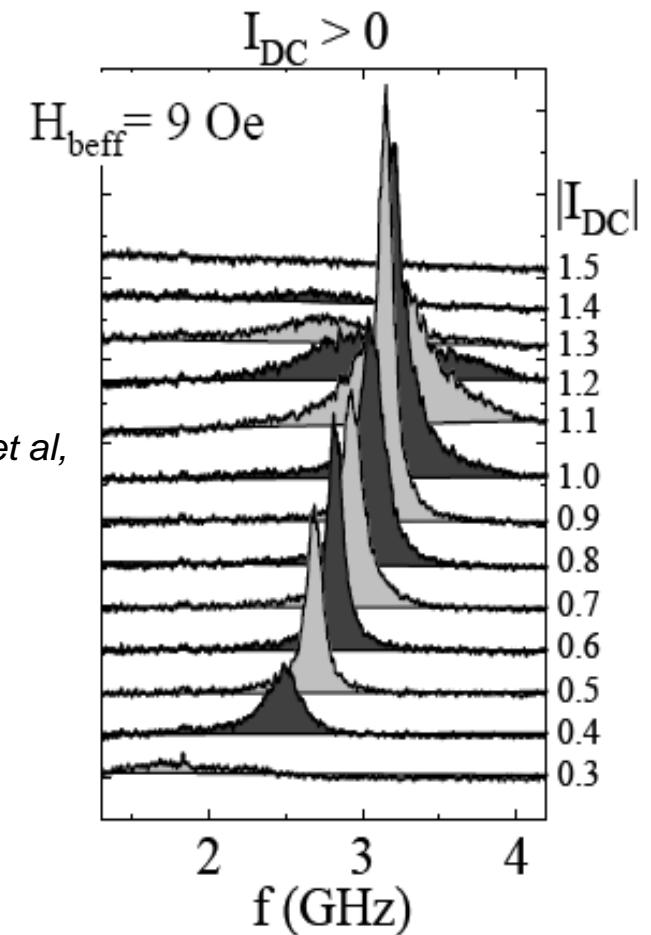


# RF components based on spin transfer

RF oscillator with perpendicular polarizer:



D.Houssamedine et al,  
Nat.Mat 2007



Injection of electrons with out-of-plane spins;  
Steady precession of the magnetization  
of the soft layer adjacent to the tunnel barrier.

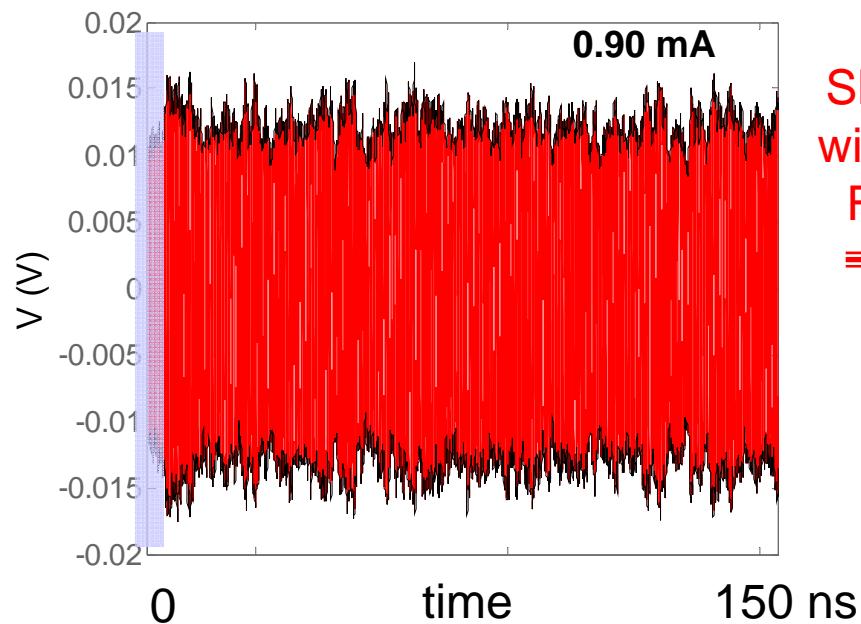
Precession (2GHz-40GHz) + Tunnel MR  $\Rightarrow$  RF voltage  
Interesting for frequency tunable RF oscillators  $\Rightarrow$  Radio opportunism

(SPINTEC patent + Lee et al, Appl.Phys.Lett.86, 022505 (2005) )

# Spin-transfer RF oscillators: linewidth and phase noise

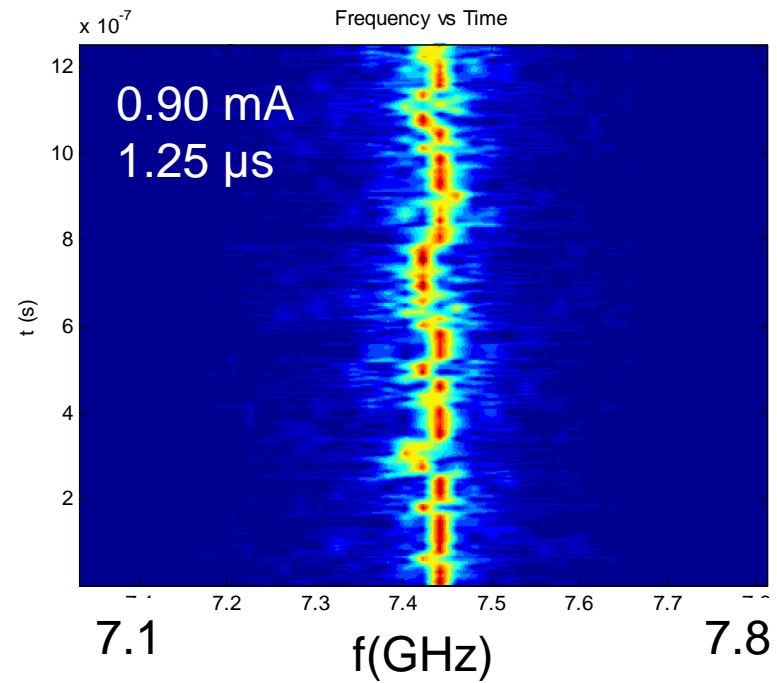
Still too large for practical applications but steady progress thanks to optimization of stack composition and shape

*Time domain measurement*



Sliding  
window  
FFT  
➡

*Time evolution of spectrum*

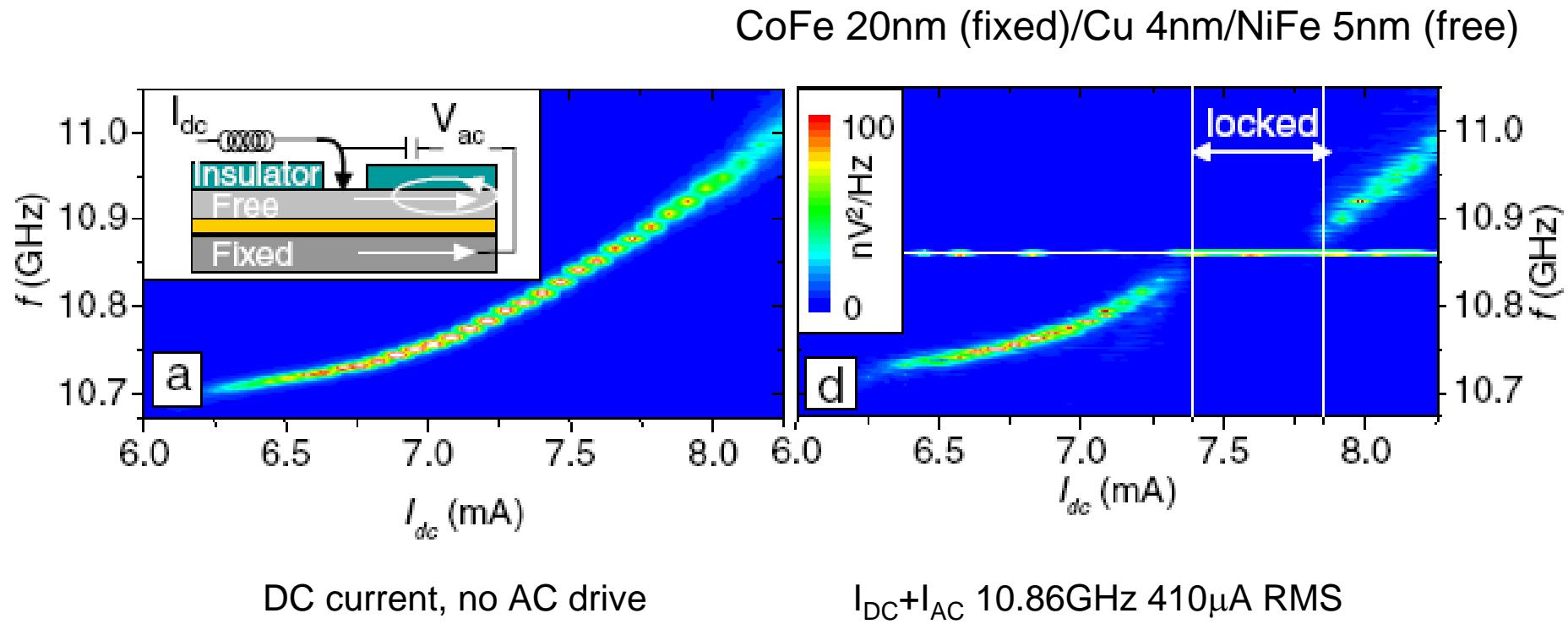


Influence of thermal fluctuations on magnetization dynamics and pillar edge modes

Increasing magnetic volume of oscillator, locking of several oscillators, locking on external source, feedback with PLL...

## RF components based on spin transfer (cont'd)

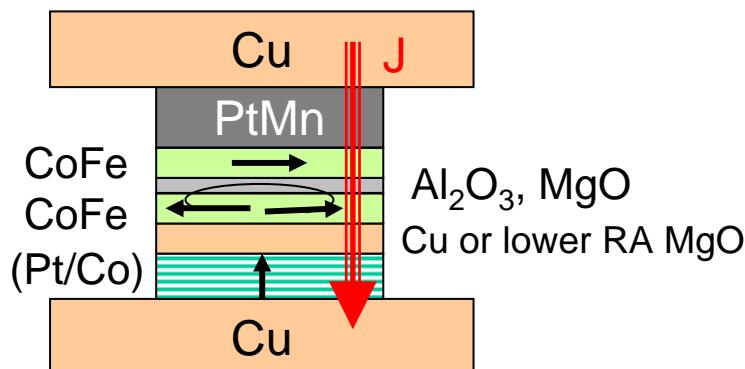
Phase locking phenomenon: Locking on an external source



*Rippard et al, PRB70, 100406 (2004)*

# Precessional switching in MRAM cell with perpendicular polarizer

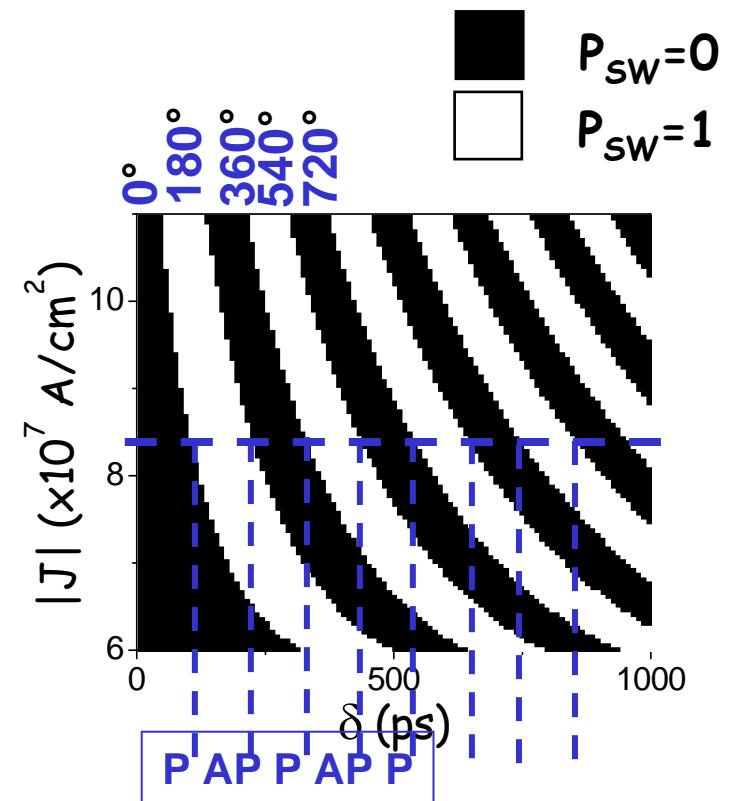
MRAM cell:  
planar MTJ+perpendicular polarizer



Switching by monopolar pulse of current  
of duration ~half precession period  
(30ps-300ps)

Macrospin LLG calculation at 0K assuming  
STT from perpendicular polarizer only.

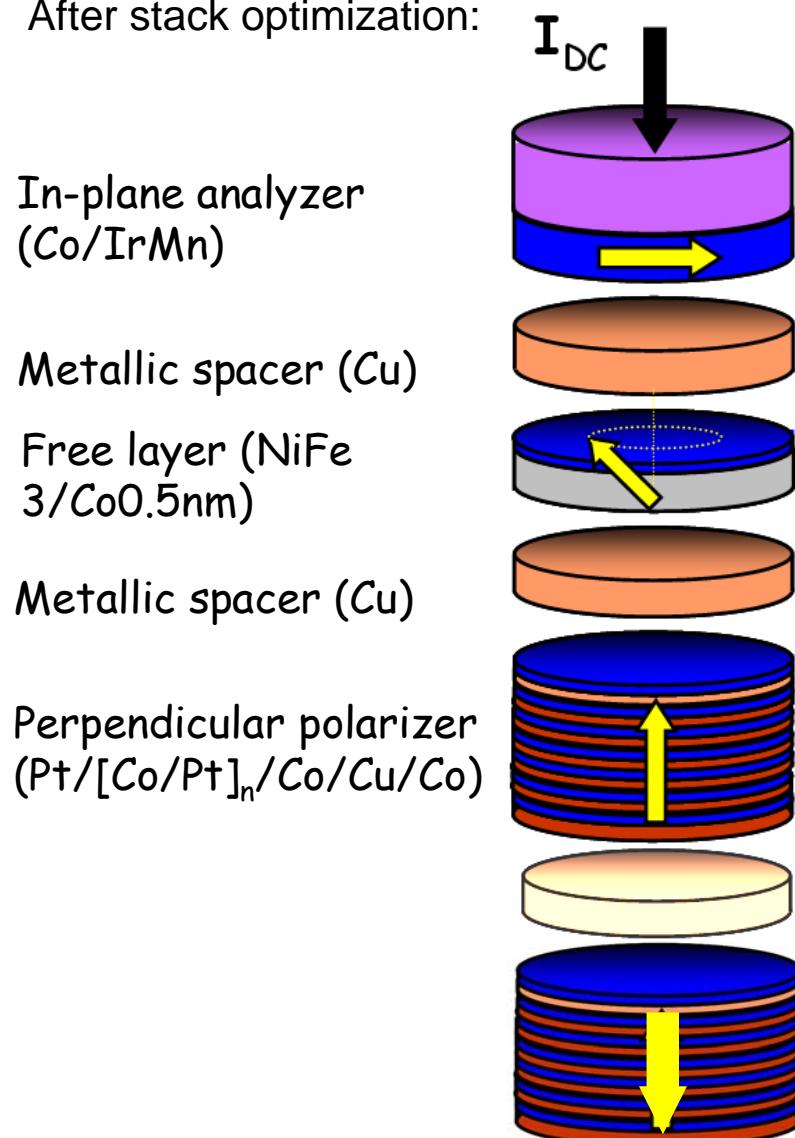
70nm\*140nm elliptical , CoFe 3nm



Same pulse duration for  $P \Rightarrow AP$  and  $AP \Rightarrow P$

# Precessional STT-switching

After stack optimization:



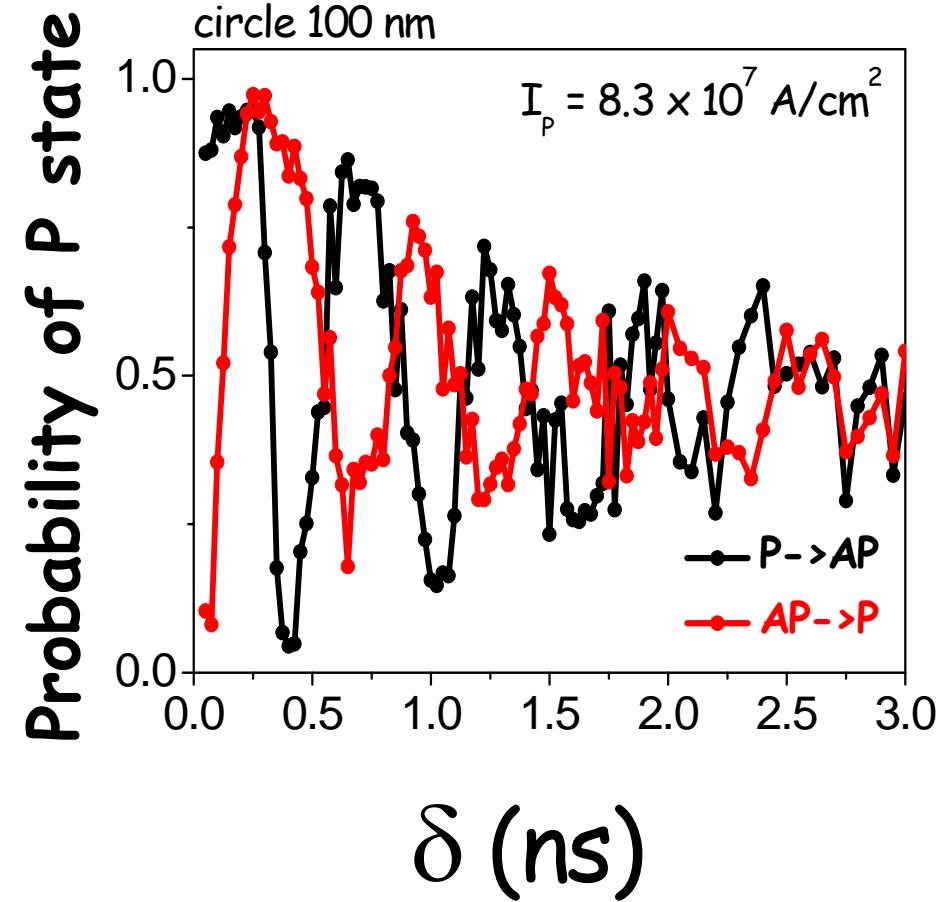
In-plane analyzer  
(Co/IrMn)

Metallic spacer (Cu)

Free layer (NiFe  
3/Co0.5nm)

Metallic spacer (Cu)

Perpendicular polarizer  
(Pt/[Co/Pt]<sub>n</sub>/Co/Cu/Co)



Ultrafast deterministic switching.

Interesting for MRAM or logic

# Conclusion

---

- GMR discovery has triggered the development of spin-electronics.
  - Played a key role in magnetic recording and other sensor applications;
- Spin-valve magnetic concept (free/pinned by exchange anisotropy) also used in MTJ  $\Rightarrow$  Spin engineering;
- Spin-transfer offers a new way to manipulate the magnetization of magnetic nanostructures (switching, steady excitations);
- For CMOS/magnetic integration, MTJ offers more suitable impedance
  - ~ few  $k\Omega$  and larger magnetoresistance than GMR;
- Increasing interest for MRAM in microelectronics industry;
- Besides MRAM, CMOS/MTJ integration quite interesting for logic, reprogrammable logic, innovative architecture;
- Frequency tunable RF oscillators interesting for wireless communications, RF interconnects, microwave assisted magnetic recording.

## Conclusion (cont'd)

---

Other more basic areas of spinelectronics are being investigated not covered in this presentation:

- Domain wall manipulation by current;
- Spin currents without charge current;
- Spin Hall effect, inverse Spin Hall effect;
- Spincaloritronics;
- Magnetic semiconductors, spintronics with semiconductors;
- Half metallic materials
- Multiferroïcs
- Spin-injection in semiconductors, spin-collect, spin-manipulation by Rashba effect;
- Graphene and Carbone nanotube spintronics;
- Spintronics with topological insulators

Certainly more to come...

# Thank you !

